

Slip 4 Additional Data Collection



SLIP 4 ADDITIONAL DATA COLLECTION

Duwamish Sediment Other Area and Southwest Bank Corrective Measure and Habitat Project Boeing Plant 2, Seattle/Tukwila, Washington

Prepared for:

The Boeing Company Seattle, Washington

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SLIP 4 ADDITIONAL DATA COLLECTION

Duwamish Sediment Other Area and Southwest Bank Corrective Measure and Habitat Project Boeing Plant 2, Seattle/Tukwila, Washington

1.0 INTRODUCTION

As part of the Duwamish Sediment Other Area (DSOA) Corrective Measure, EPA identified four small areas within Slip 4 to be dredged (see Figure 1). A review of the Slip 4 data was provided in Appendix N of the Corrective Measure Alternatives Study (AMEC and FSI 2011). The dredge depths in the four areas were a nominal 2, 3, or 4 feet, based on existing data or weight of evidence. EPA also required post-construction/pre-backfill core samples to be collected within the footprint of each of the four dredge areas (Post-Construction Core Sampling Work Plan; AMEC et al. 2012).

Boeing completed the dredging in the four areas in early December 2014, and the post-construction core samples were collected in accordance with the approved Post-Construction Core Sampling Work Plan (AMEC et al. 2012). The results of the post-construction core sampling indicated that elevated concentrations of polychlorinated biphenyls (PCBs) were present at the bottom of the dredge cuts in one of the four areas.

This report describes the results of the initial post-construction coring and additional investigations that were conducted to determine the nature and extent of elevated PCB concentrations within the Boeing-owned portion of Slip 4.

The coordinates for the locations of core samples presented in this report are provided in Table 1.

2.0 DECEMBER 2014 POST-CONSTRUCTION CORE SAMPLES

Results for post-construction core samples collected in December 2014 showed that metals concentrations were below the Sediment Management Standards Sediment Quality Standards (SQS; Washington Administrative Code [WAC] 173-204-320) in all of the dredge areas (Table 2). Total PCB concentrations were below the SQS in three of the four areas (Table 2 and Figure 2). One dredge area had elevated PCB concentrations in all the sample intervals analyzed. The dredge depth in this area was on the order of 4 to 5 feet, and PCB concentrations were elevated at least 2 feet below the bottom of the dredge cut (approximately 6 to 7 feet below the original mudline). These results were not expected, as results from previous core samples collected in the area indicated that elevated PCB concentrations did not extend more than 2 to 3 feet below the previous mudline. It appeared that

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elevated PCBs concentrations were confined to what appeared to be recently deposited material, and that the native underlying sediments did not contain PCBs. The core summary logs and sample photographs are provided in Attachment A.

Based on the results from the core samples collected in December 2014, additional investigations of the Slip 4 area were conducted, as described below.

3.0 PHASE 1 SLIP 4 ADDITIONAL CORE SAMPLE COLLECTION

Based on the results of the December 2014 post-construction cores, the Slip 4 Additional Sediment Cores work plan (AMEC 2014) was submitted to and approved by EPA.

Samples were collected at the four locations shown on Figure 3. At locations SD-SL4-003 and SD-SL4-004, elevated concentrations of PCBs extended to approximately 5 feet below the mudline, and at SD-SL4-001 and SD-SL4-002 elevated concentrations of PCBs extended to approximately 8 feet below the mudline (Table 3 and Figure 3). Again, it appeared that elevated PCB concentrations were confined to what appeared to be recently deposited material and that the native underlying sediments did not contain PCBs. The core summary logs and sample photographs are provided in Attachment A.

Subsequent to receiving the analytical results, Boeing learned that at least two earlier dredging events had been conducted in Slip 4 in 1980 and 1996. Based on the plans for the 1980 dredge event, all of Slip 4 outside of the Boeing property was to be dredged to a depth corresponding to -15 feet mean lower low water (MLLW) plus some allowable overdredge depth (probably on the order of 2 feet). In 1996, Slip 4 was to be dredged, adjacent to the former Crowley pier, to a depth corresponding to -15 feet MLLW, again with some allowable overdredge.

The plans do not indicate how far the dredging extended onto the Boeing property, but it is assumed that some dredging to the full dredge depth extended onto the Boeing property.

Results for the Phase 1 Slip 4 Additional core samples indicate that elevated PCB concentrations occurred in sediments between -14 and -20 feet MLLW. The elevation ranges where elevated PCB concentrations were observed are not inconsistent with the earlier proposed navigation dredging depths and allowable over depth.

Based on this information, it was assumed that the depths where elevated PCB concentrations were observed can likely be explained by historic dredging conducted in the slip. This hypothesis is consistent with the physical conceptual site model (CSM) for the DSOA that was presented in the



Corrective Measure Alternatives Study (AMEC and FSI 2011), which suggested that navigation dredging likely influenced the depth of contamination. If the CSM explains the contamination at depth, then it was anticipated that the depth of contamination along the shoreline bank would be less than in the main navigable portion of the slip where the prior samples were collected.

4.0 PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE COLLECTION

A second phase of core sample collection was conducted at the locations shown on Figure 4 (AMEC 2015). Samples were collected along the shoreline and offshore to bound the extent of elevated concentrations of PCBs within a majority of the Boeing-owned portion of Slip 4.

The results from Phase 2 (Table 4 and Figure 4) showed that elevated concentrations of PCBs along the shoreline did not extend below 1 to 2 feet below mudline (SD-SL4-005, SD-SL4-006, SD-SL4-007, SD-SL4-010, and SD-SL4-012), except at SD-SL4-008, where elevated concentrations extended to 6 feet below mudline. Elevated PCB concentrations at offshore locations SD-SL4-009 and SD-SL4-011 extended 8 and 6 feet below mudline, respectively. As with the other two sampling events, it appeared that elevated PCBs concentrations were confined to what appeared to be recently deposited material and that the native underlying sediments did not contain PCBs. The core summary logs and sample photographs are provided in Attachment A.

Except for SD-SL4-008, the vertical extent of elevated PCB concentrations were consistent with the CSM; the depths where elevated PCB concentrations were observed were shallower along the shoreline and deeper offshore.

5.0 DATA QUALITY REVIEW

The chain-of-custody forms are provided in Attachment B. Results of the Stage 2B data validation on the Slip 4 data are reported in Attachment C. A summary of the data validation is presented below.

5.1 PCB ANALYSES

Documentation for the PCB analyses was found to be clear and complete. The calibration data demonstrated acceptable instrument performance, and the laboratory control sample results demonstrated acceptable accuracy and precision. Multiple analysis results were reduced to the most appropriate to use. Some results were estimated due to dual column variability. Except for data replaced by another result, PCB data were acceptable for use as qualified.

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5.2 METALS ANALYSES

Documentation for the metals analyses was found to be clear and complete. The calibration data demonstrated acceptable instrument performance, and the method blank, laboratory control sample (LCS), and standard reference material results demonstrated acceptable laboratory precision and accuracy. One zinc result was estimated based on the matrix spike (MS) recovery. The metals data were acceptable for use as qualified.

5.3 GENERAL CHEMISTRY

The documentation for general chemistry was found to be clear and complete. Calibration data indicated acceptable performance, and method blank and LCS results demonstrate acceptable laboratory accuracy. Some data were estimated based on laboratory triplicate, MS/matrix spike duplicate, and MS and standard reference material (SRM) recoveries. The general chemistry results were acceptable for use as qualified.

6.0 SUMMARY

Results of sediment core sampling described in this report showed that the depth of sediments containing elevated PCB concentrations was shallower near the shoreline and deeper offshore (Figure 5), which is consistent with the CSM. The CSM, the depth of elevated PCB concentrations, and the evidence that native sediments were "clean" were used to develop a new dredge plan, which was subsequently implemented with approval by EPA on February 10, 2015.

7.0 REFERENCES

- AMEC Environment & Infrastructure, Inc. (AMEC). 2014. Slip 4 Additional Sediment Cores, Boeing Plant 2, Seattle/Tukwila, Washington. Prepared for The Boeing Company, Seattle, Washington.
- ——— 2015. Slip 4 Additional Sediment Cores, Phase 2, Boeing Plant 2, Seattle/Tukwila, Washington. Prepared for The Boeing Company, Seattle, Washington.
- AMEC Environment & Infrastructure, Inc., and Floyd|Snider, Inc. (AMEC and FSI). 2011. Duwamish Sediment Other Area and Southwest Bank Corrective Measure Alternatives Study, Boeing Plant 2, Seattle/Tukwila, Washington. Prepared for The Boeing Company, Seattle, Washington.
- AMEC Environment & Infrastructure, Inc., Dalton, Olmsted & Fuglevand, Inc., and Floyd|Snider, Inc. (AMEC et al.). 2012. Post-Construction Core Sampling Work Plan, Appendix F in Final Construction Quality Assurance Project Plan, Duwamish Sediment Other Area and Southwest Bank Corrective Measure and Habitat Project, Boeing Plant 2, Seattle/Tukwila, Washington. Prepared for The Boeing Company, Seattle, Washington.



LOCATION OF CORE SAMPLES COLLECTED IN SLIP 4

			(WA SP	ane Coordinates C North urvey Feet)		Depth Interval
Location	Date	Time	Easting	Northing	Sample ID	(Feet Below Sediment Surface)
SD-PCC001	12/9/2014	12:19	1273280	198777	SD-PCC001-A	0 to 0.33
					SD-PCC001-B	0.33 to 1
					SD-PCC001-C	1 to 2
					SD-PCC001-D	2 to 3
SD-PCC002	12/9/2014	11:58	1273255	198752	SD-PCC002-A	0 to 0.33
					SD-PCC002-B	0.33 to 1
					SD-PCC002-C	1 to 2
					SD-PCC002-D	2 to 3
SD-PCC003	12/8/2014	11:55	1273176	198687	SD-PCC003-A	0 to 0.33
					SD-PCC003-B	0.33 to 1
					SD-PCC003-C	1 to 2
					SD-PCC003-D	2 to 3
SD-PCC004	12/8/2014	10:49	1273031	198522	SD-PCC004-A	0 to 0.33
					SD-PCC004-B	0.33 to 1
					SD-PCC004-C	1 to 2
					SD-PCC004-D	2 to 3
SD-PCC005	12/8/2014	11:25	1272971	198515	SD-PCC005-A	0 to 0.33
					SD-PCC005-B	0.33 to 1
					SD-PCC005-C	1 to 2
					SD-PCC005-D	2 to 3



LOCATION OF CORE SAMPLES COLLECTED IN SLIP 4

			(WA SP	ne Coordinates C North urvey Feet)		Depth Interval
Location	Date	Time	Easting	Northing	Sample ID	(Feet Below Sediment Surface)
SD-SL4-001	12/22/2014	9:50	1273119	198630	SD-SL4-001-0000	0 to 1
					SD-SL4-001-0010	1 to 2
					SD-SL4-001-0020	2 to 3
					SD-SL4-001-0030	3 to 4
					SD-SL4-001-0040	4 to 5
					SD-SL4-001-0050	5 to 6
					SD-SL4-001-0060	6 to 7
					SD-SL4-001-0070	7 to 8
					SD-SL4-001-0080	8 to 9
SD-SL4-002	12/22/2014	10:19	1273149	198661	SD-SL4-002-0000	0 to 1
					SD-SL4-002-0010	1 to 2
					SD-SL4-002-0020	2 to 3
					SD-SL4-002-0030	3 to 4
					SD-SL4-002-0040	4 to 5
					SD-SL4-002-0050	5 to 6
					SD-SL4-002-0060	6 to 7
					SD-SL4-002-0070	7 to 8
					SD-SL4-002-0080	8 to 9
SD-SL4-003	12/22/2014	11:24	1273208	198711	SD-SL4-003-0000	0 to 1
					SD-SL4-003-0010	1 to 2
					SD-SL4-003-0020	2 to 3
					SD-SL4-003-0030	3 to 4
					SD-SL4-003-0040	4 to 5
					SD-SL4-003-0050	5 to 6
					SD-SL4-003-0060	6 to 7
					SD-SL4-003-0070	7 to 8
					SD-SL4-003-0080	8 to 9



LOCATION OF CORE SAMPLES COLLECTED IN SLIP 4

			(WA SP	nne Coordinates C North urvey Feet)		Depth Interval
Location	Date	Time	Easting	Northing	Sample ID	(Feet Below Sediment Surface)
SD-SL4-004	12/22/2014	10:49	1273176	198687	SD-SL4-004-0000	0 to 1
					SD-SL4-004-0010	1 to 2
					SD-SL4-004-0020	2 to 3
					SD-SL4-004-0030	3 to 4
					SD-SL4-004-0040	4 to 5
					SD-SL4-004-0050	5 to 6
					SD-SL4-004-0060	6 to 7
					SD-SL4-004-0070	7 to 8
					SD-SL4-004-0080	8 to 9
SD-SL4-005	1/15/2015	10:28	1273224	198693	SD-SL4-005-0000	0 to 1
			1273224		SD-SL4-005-0010	1 to 2
					SD-SL4-005-0020	2 to 3
					SD-SL4-005-0030	3 to 4
					SD-SL4-005-0040	4 to 5
					SD-SL4-005-0050	5 to 6
					SD-SL4-005-0060	6 to 7
SD-SL4-006	1/15/2015	9:52	1273191	198667	SD-SL4-006-0000	0 to 1
					SD-SL4-006-0010	1 to 2
					SD-SL4-006-0020	2 to 3
					SD-SL4-006-0030	3 to 4
					SD-SL4-006-0040	4 to 5
					SD-SL4-006-0050	5 to 6
			1273176		SD-SL4-006-0060	6 to 7



LOCATION OF CORE SAMPLES COLLECTED IN SLIP 4

			(WA SP	ne Coordinates C North urvey Feet)		Depth Interval
Location	Date	Time	Easting	Northing	Sample ID	(Feet Below Sediment Surface)
SD-SL4-007	1/15/2015	9:27	1273166	198644	SD-SL4-007-0000	0 to 1
					SD-SL4-007-0010	1 to 2
					SD-SL4-007-0020	2 to 3
					SD-SL4-007-0030	3 to 4
					SD-SL4-007-0040	4 to 5
					SD-SL4-007-0050	5 to 6
					SD-SL4-007-0060	6 to 7
					SD-SL4-007-0070	7 to 8
					SD-SL4-007-0080	8 to 9
SD-SL4-008	1/15/2015	11:20	1273138	198611	SD-SL4-008-0000	0 to 1
					SD-SL4-008-0010	1 to 2
					SD-SL4-008-0020	2 to 3
					SD-SL4-008-0030	3 to 4
					SD-SL4-008-0040	4 to 5
					SD-SL4-008-0050	5 to 6
					SD-SL4-008-0060	6 to 7
					SD-SL4-008-0070	7 to 8
					SD-SL4-008-0080	8 to 9
SD-SL4-009	1/14/2015	11:46	1273076	198604	SD-SL4-009-0000	0 to 1
					SD-SL4-009-0010	1 to 2
					SD-SL4-009-0020	2 to 3
					SD-SL4-009-0030	3 to 4
					SD-SL4-009-0040	4 to 5
					SD-SL4-009-0050	5 to 6
					SD-SL4-009-0060	6 to 7
					SD-SL4-009-0070	7 to 8
					SD-SL4-009-0080	8 to 9



LOCATION OF CORE SAMPLES COLLECTED IN SLIP 4

Slip 4 Additional Data Collection
Duwamish Sediment Other Area and Southwest Bank
Corrective Measure and Habitat Project
Boeing Plant 2
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			(WA SP	nne Coordinates C North urvey Feet)		Depth Interval
Location	Date	Time	Easting	Northing	Sample ID	(Feet Below Sediment Surface)
SD-SL4-010	1/14/2015	12:30	1273092	198577	SD-SL4-010-0000	0 to 1
					SD-SL4-010-0010	1 to 2
					SD-SL4-010-0020	2 to 3
					SD-SL4-010-0030	3 to 4
					SD-SL4-010-0040	4 to 5
					SD-SL4-010-0050	5 to 6
					SD-SL4-010-0060	6 to 7
SD-SL4-011	1/14/2015	11:11	1273034	198574	SD-SL4-011-0000	0 to 1
					SD-SL4-011-0010	1 to 2
					SD-SL4-011-0020	2 to 3
					SD-SL4-011-0030	3 to 4
					SD-SL4-011-0040	4 to 5
					SD-SL4-011-0050	5 to 6
					SD-SL4-011-0060	6 to 7
					SD-SL4-011-0070	7 to 8
					SD-SL4-011-0080	8 to 9
					SD-SL4-011-0090	9 to 10
SD-SL4-012	1/15/2015	12:49	1273056	198555	SD-SL4-012-0000	0 to 1
					SD-SL4-012-0010	1 to 2
					SD-SL4-012-0020	2 to 3
					SD-SL4-012-0030	3 to 4
					SD-SL4-012-0040	4 to 5

Abbreviation(s)

NAD 83 = North American Datum of 1983 WA SPC = Washington State Plane Coordinates



DECEMBER 2014 POST-CONSTRUCTION CORE SAMPLE RESULTS 1,2

	Sediment	Sample_ID	SD-P	CC001	I-A	SD-PC	C001	I-B	SD-P	CC001	1-C	SD-P	CC00	2-A	SD-P0	C002	2-B	SD-P	CC002	2-C	SD-P	CC00	3-A	SD-P	CC00	3-B	SD-P	CC003	;-C
	Management	Sample Date	12/9	9/2014	1	12/9	/2014	ļ.	12/9	9/2014	4	12/	9/201	4	12/9	9/2014	ļ	12/	9/2014	4	12/8	8/201	4	12/	8/201	4	12/	8/2014	
	Standards	Sample Interval	0 to	10 cr	n	10 cn	n to 1	ft	1 t	o 2 ft		0 to	10 c	m	10 cn	n to 1	ft	1	to 2 ft		0 to	10 cr	n	10 c	m to 1	ft	1 1	to 2 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²																								
Total Organic Carbon (percent)	_		0.120			0.081			0.109			1.11			0.902			2.03			1.44			1.50			1.80		
Metals (mg/kg Dry weight)																													
Arsenic	57		1.78			1.31			1.58			3.47			4.38			3.36			11.16			7.31			4.64		
Cadmium	5.1		0.2	J		0.2	U		0.2	U		0.2	U		0.2	J		0.3			1.3			0.8			0.5		
Chromium	260		11.1			12.8			10.8			12.2			15.1			15.7			37.8			26.2			17.7		
Copper	390		10.0			15.3			9.5			13.6			19.3			20.7			49.4			34.7			30.0		
Lead	450		2	כ		2	J		2	U		3			4			5			67			58			24		i
Mercury	0.41		0.03	כ		0.03	J		0.03	U		0.04			0.05			0.03			0.29			0.04			0.07		
Silver	6.1		0.3	U		0.4	U		0.4	U		1.2			0.7			0.4											
Zinc	410		27			30			26			31			34			38			132		J	104			66		
PCBs (µg/kg Dry-Weight)																													
Aroclor 1016	_		3.9	U		3.9	U		3.9	U		3.8	U		3.9	U		3.9	U		6.7	U		3.8	U		3.8	U	
Aroclor 1221	_		3.9	J		3.9	U		3.9	U		3.8	U		3.9	J		3.9	U		6.7	U		3.8	U		3.8	U	
Aroclor 1232	_		3.9	כ		9.8	Υ	UY	3.9	U		3.8	J		3.9	כ		3.9	U		6.7	U		3.8	U		3.8	U	
Aroclor 1242	_		3.9	כ		3.9	J		3.9	U		3.8	J		3.9	כ		3.9	U		6.7	U		3.8	U		3.8	U	
Aroclor 1248	_		8.6			3.9	U		3.9	U		3.8	U		3.9	J		3.9	U		1700	Υ	UY	1200	Υ	UY	480	Υ	UY
Aroclor 1254	_		26			3.9	U		3.9	U		13			3.9	U		3.9	U		6400			5100			2100		
Aroclor 1260	_		8.1			3.9	U		3.9	U		6.6			3.9	U		3.9	U		840	Υ	UY	770	U		150	Υ	UY
Total PCBs 3	130		42.7			9.8	Υ	UY	3.9	U		19.6			3.9	U		3.9	U		6400			5100			2100		
Total PCBs (mg/kg-OC) 4	12		NA			NA			NA			1.8			0.4	U		0.2	U		444			340			117		i



DECEMBER 2014 POST-CONSTRUCTION CORE SAMPLE RESULTS 1,2

Slip 4 Additional Data Collection Duwamish Sediment Other Area and Southwest Bank Corrective Measure and Habitat Project Boeing Plant 2 Seattle/Tukwila, Washington

	Sediment	Sample_ID	SD-P	CC00	3-D	SD-P	CC004	1-A	SD-P	CC004	4-B	SD-P	CC004	4-C	SD-P	CC00	5-A	SD-P	CC00	5-B	SD-P	CC00	5-C
	Management	Sample Date	12/	8/201	4	12/	8/2014	4	12/3	3/2014	4	12/8	8/201	4	12/	8/201	4	12/	8/201	4	12/	8/2014	4
	Standards	Sample Interval	2	to 3 ft		0 to	10 cr	n	10 cr	n to 1	ft	1 t	o 2 ft		0 to	10 cr	m	10 cı	n to 1	ft	11	to 2 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²																		
Total Organic Carbon (percent)			0.37			1.49			0.297			0.511			0.584			0.478			0.399		
Metals (mg/kg Dry weight)																							
Arsenic	57		_			6.45			1.17			3.30			2.69			2.35			2.08		
Cadmium	5.1		_			0.3	U		0.2	J		0.3	U		0.3	U		0.3	J		0.3	U	
Chromium	260		_			10.0			9.7			11.6			12.0			13.3			13.4		
Copper	390					14.0			11.1			18.7			15.9			18.5			17.9		
Lead	450		_			3	U		2	U		3	U		3			3	U		3	U	
Mercury	0.41		_			0.03	U		0.03	U		0.04			0.03	U		0.02	U		0.03	U	
Silver	6.1		_			0.4	U		0.3	U		0.4	U										
Zinc	410		_			26			21			25			29			28			27		
PCBs (µg/kg Dry-Weight)																							
Aroclor 1016	1		20	U		3.9	U		4.0	U		3.9	U		3.8	U		3.9	J		4.0	U	
Aroclor 1221			20	U		3.9	U		4.0	U		3.9	U		3.8	U		3.9	U		4.0	U	
Aroclor 1232			20	U		3.9	U		20	Υ	UY	3.9	כ		3.8	U		3.9	J		4.0	U	
Aroclor 1242			20	U		3.9	U		4.0	J		3.9	כ		3.8	U		3.9	J		4.0	U	
Aroclor 1248			430	Υ	UY	16	Υ	UY	4.0	J		3.9	כ		15	Υ	UY	3.9	J		4.0	U	
Aroclor 1254			990			34			4.0	J		3.9	U		29			3.9	U		4.0	U	
Aroclor 1260			300			8.3			4.0	U		3.9	U		11			3.9	U		4.0	U	
Total PCBs 3	130		1290			42.3			20	Υ	UY	3.9	U		40			3.9	U		4.0	U	
Total PCBs (mg/kg-OC) 4	12		NA			2.8			NA			0.8	U		6.8			NA			NA		

Note(s)

- 1. Laboratory qualifiers (Q1) are defined as follows:
 - U = analyte not detected at reporting limit presented.
 - Y = The analyte is not detected at or above the reported concentration. The reporting limit is raised due to chromatographic interference. The Y flag is equivalent to the U flag with a raised reporting limit.
- 2. Validation qualifiers (Q2) are defined as follows:
 - UY = The reporting limit was elevated due to chromatographic overlap with related compounds. The material was analyzed for, but was not detected above, the level of the associated value. J = The analyte was positively identified. The associated numerical value is the approximate concentration of the analyte in the sample.
- 3. Total PCBs calculated by summing results for detected congeners or, if all not detected, using the highest reporting limit for non-detected congeners.
- 4. NA: Carbon outside the range for normalization (<0.5 % or >4.0%).

Abbreviation(s)

cm = centimeters

ft = feet

mg/kg Dry-Weight = milligrams per kilogram dry weight mg/kg-OC = milligrams per kilogram organic carbon

PCBs = polychlorinated biphenyls

SQS = Sediment Management Standards Sediment Quality Standards (173-204-320 WAC)

μg/kg Dry-Weight = micrograms per kilogram dry weight

WAC = Washington Administrative Code



PHASE 1 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1, 2

		Sample Location													SD-S	SL4-00)1												
	Sediment	Sample Date	12/2	22/201	4	12/2	22/201	4	12/2	22/20 ⁻	4	12/2	22/201	14	12/2	2/201	4	12/2	2/201	4	12/2	22/201	4	12/	22/201	14	12/2	22/2014	4
	Management	Sample ID	SD-SL4	4-001-	0000	SD-SL	4-001-	0010	SD-SL	4-001·	-0020	SD-SL4	1-001·	-0030	SD-SL4	-001-	0040	SD-SL4	l-001-	0050	SD-SL4	4-001-	0060	SD-SL	4-001-	-0070	SD-SL	4-001-(0800
	Standards	Sample Interval	0 1	to 1 ft		1	to 2 ft	:	2	to 3 ft	<u> </u>	3 1	to 4 ft	t	4 t	o 5 ft		5 t	o 6 ft		6	to 7 ft		7	to 8 ft	:	8	to 9 ft	
Analyte	SQS		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²
Total Organic Carbon (percent)	_		1.030			0.527			1.490			1.160			0.829			1.710			1.670			1.230			1.280		
PCBs (µg/kg Dry-Weight)																													
Aroclor 1016	_		3.9	U		3.8	U		20	U		19	U		20	U		40	U		80	U		38	U		3.9	U	
Aroclor 1221	_		3.9	U		3.8	U		20	U		19	U		20	U		40	U		80	U		38	U		3.9	U	
Aroclor 1232	_		3.9	U		3.8	U		20	U		19	U		20	U		40	U		80	U		38	U		3.9	U	
Aroclor 1242	_		3.9	U		3.8	U		20	U		19	U		20	U		40	U		80	U		38	U		3.9	U	
Aroclor 1248	_		66			84			220			170			150			460			1400			360			3.9	U	
Aroclor 1254	_		120			170			470			480			460			1200			3600			1000			5.1		
Aroclor 1260	_		39		J	76			100		J	88		J	140		J	190		J	500		J	160		J	3.9	U	
Total PCBs 3	130		225		J	330			790		J	738		J	750		J	1850		J	5500		J	1520		J	5.1		
Total PCBs (mg/kg-OC) 4	12		22		J	63			53		J	64		J	90		J	108		J	329		J	124		J	0.4		



PHASE 1 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1, 2

		Sample Location													SD-S	SL4-0	02												
	Sediment	Sample Date	12/2	22/201	4	12/2	22/201	4	12/2	22/20	14	12/2	22/20 ⁻	14	12/2	22/201	4	12/2	2/201	4	12/2	22/201	4	12/2	22/201	14	12/	22/201	4
	Management	Sample ID	SD-SL4	1-002-	0000	SD-SL4	1-002-	0010	SD-SL	4-002	-0020	SD-SL4	1-002	-0030	SD-SL4	1-002-	0040	SD-SL4	-002-	0050	SD-SL4	4-002-	0060	SD-SL	4-002·	-0070	SD-SL4	4-002-	0800
	Standards	Sample Interval	0 1	to 1 ft		1 1	to 2 ft		2	to 3 f	t	3 1	to 4 f	t	4 1	o 5 ft		5 1	o 6 ft		6	to 7 ft		7	to 8 ft	t	8	to 9 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²
Total Organic Carbon (percent)	_		1.300			0.476			0.857			1.210			1.090			0.786			2.210			1.160			1.480		J
PCBs (µg/kg Dry-Weight)																													
Aroclor 1016	_		4	U		12	U		19	U		380	U		19	U		20	U		32	U		20	U		3.8	U	
Aroclor 1221	_		4	U		12	U		19	U		380	U		19	U		20	כ		32	U		20	U		3.8	U	
Aroclor 1232	_		4	U		12	U		19	U		380	U		19	U		20	U		32	U		20	U		3.8	U	
Aroclor 1242	_		4	U		12	U		19	U		380	U		19	U		20	כ		32	U		20	U		3.8	U	
Aroclor 1248	_		65			81			110			380	U		180			220			2000			200	Υ	UY	19	Υ	UY
Aroclor 1254	_		140			210			270			1000			540			540			5300			490			3.8	U	
Aroclor 1260	_		48			38			110			7400		J	120			150			850			82			3.8	U	
Total PCBs ³	130		253			329			490			8400		J	840			910			8150			572			19	Υ	
Total PCBs (mg/kg-OC) 4	12		19.5			NA			57			694		J	77			116			369			49			1.3	Υ	



PHASE 1 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1, 2

		Sample Location													SD-S	SL4-00	03												
	Sediment	Sample Date	12/2	2/201	4	12/2	22/201	14	12/2	22/20	14	12/2	22/20	14	12/2	2/201	4	12/2	22/201	4	12/2	22/201	14	12/2	22/201	14	12/2	22/2014	
	Management	Sample ID	SD-SL4	l-003-(0000	SD-SL4	1-003 -	-0010	SD-SL4	4-003·	-0020	SD-SL4	4-003	-0030	SD-SL4	I-003-	0040	SD-SL4	1-003-0	0050	SD-SL4	4-003-	-0060	SD-SL4	4 - 003	-0070	SD-SL4	4-003-00	080
	Standards	Sample Interval	0 t	o 1 ft		11	to 2 ft	į	2	to 3 ft	t	3 1	to 4 f	t	4 t	o 5 ft		5 1	to 6 ft		6	to 7 ft	1	7	to 8 ft	t	8	to 9 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1	1 Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹ C	Q2 ²									
Total Organic Carbon (percent)	_		2.490			1.970			0.935			0.674			0.096			0.549			0.057			0.680			0.836		
PCBs (µg/kg Dry-Weight)																													
Aroclor 1016			20	U		20	U		27	U		20	U		3.9	U		3.9	U		3.9	U		3.8	U		3.8	U	
Aroclor 1221	_		20	U		20	U		27	U		20	U		3.9	U		3.9	U		3.9	U		3.8	U		3.8	U	
Aroclor 1232	_		20	U		20	U		27	U		20	U		3.9	U		3.9	U		3.9	U		3.8	U		3.8	U	
Aroclor 1242	_		20	U		20	U		27	U		20	U		3.9	U		3.9	U		3.9	U		3.8	U		3.8	U	
Aroclor 1248	_		120			88			1200			310			40			3.9	U		3.9	U		3.8	U		3.8	U	
Aroclor 1254	_		250			210			3900			910			120			4.4			3.9	U		3.8	U		3.8	U	
Aroclor 1260	_		92			56			530			120			16			3.9	U		3.9	U		3.8	U		3.8	U	
Total PCBs 3	130		462			354			5630			1340			176			4.4			3.9	U		3.8	U		3.8	U	
Total PCBs (mg/kg-OC) 4	12		18.6			18			602			199			NA			0.8			NA			0.6	U		0.5	U	



PHASE 1 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1,2

Slip 4 Additional Data Collection
Duwamish Sediment Other Area and Southwest Bank
Corrective Measure and Habitat Project
Boeing Plant 2
Seattle/Tukwila, Washington

		Sample Location									SD-SI	_4-004								
	Sediment	Sample Date	12/2	22/201	4	12/2	22/201	4	12/2	22/201	4	12/2	2/201	4	12/2	22/201	4	12/2	22/201	4
	Management	Sample ID	SD-SL4	4-004-	-0030	SD-SL4	1-004-	0040	SD-SL4	1-004-	0050	SD-SL4	-004-	0060	SD-SL	4-004-	0070	SD-SL	1-004-	0080
	Standards	Sample Interval	3	to 4 ft		4	to 5 ft		5	to 6 ft		61	o 7 ft		7	to 8 ft		8	to 9 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²									
Total Organic Carbon (percent)	_		1.490			0.151			0.032			0.085			0.137			0.682		
PCBs (µg/kg Dry-Weight)																				
Aroclor 1016	_		20	U		20	U		3.8	U		3.8	U		3.9	U		4	U	
Aroclor 1221	_		20	U		20	U		3.8	U		3.8	U		3.9	U		4	U	
Aroclor 1232	_		20	U		20	U		3.8	U		3.8	U		3.9	U		4	U	
Aroclor 1242	_		20	U		20	U		3.8	U		3.8	U		3.9	U		4	U	
Aroclor 1248	_		700			46			3.8	U		3.8	U		3.9	U		4	U	
Aroclor 1254	_		2500			150			4.5			3.8	U		3.9	U		4	U	
Aroclor 1260	_		420			31			3.8	U		3.8	U		3.9	U		4	U	
Total PCBs 3	130		3620			227			4.5			3.8	U		3.9	U		4	U	
Total PCBs (mg/kg-OC) 4	12		243			NA			NA			NA			NA			0.6	U	

Note(s

- 1. Laboratory qualifiers (Q1) are defined as follows:
 - U = analyte not detected at reporting limit presented.
 - Y = The analyte is not detected at or above the reported concentration. The reporting limit is raised due to chromatographic interference. The Y flag is equivalent to the U flag with a raised reporting limit.
- 2. Validation qualifiers (Q2) are defined as follows:
 - UY = The reporting limit was elevated due to chromatographic overlap with related compounds. The material was analyzed for, but was not detected above, the level of the associated value.
- J = The analyte was positively identified. The associated numerical value is the approximate concentration of the analyte in the sample.
- 3. Total PCBs calculated by summing results for detected congeners or, if all not detected, using the highest reporting limit for non-detected congeners.
- 4. NA: Carbon outside the range for normalization (<0.5 % or >4.0%).

Abbreviation(s)

ft = feet

mg/kg-OC = milligrams per kilogram organic carbon

PCBs = polychlorinated biphenyls

SQS = Sediment Management Standards Sediment Quality Standards (173-204-320 WAC)

μg/kg Dry-Weight = micrograms per kilogram dry weight

WAC = Washington Administrative Code



PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1, 2

		Sample Location										SD-S	L4-00	5									
	Sediment	Sample Date	1/15	/2015		1/15	5/2015		1/15	/2015	5	1/15	/2015		1/1	5/2015	5	1/15	5/2015	5	1/1	5/2015	<u> </u>
	Management	Sample ID	SD-SL4	-005-0	0000	SD-SL4	-005-0	010	SD-SL4	-005-0	0020	SD-SL4	-005-0	030	SD-SL4	-005-0	0040	SD-SL4	-005-0	0050	SD-SL4	I-005-0	0060
	Standards	Sample Interval	0 t	o 1 ft		1 t	o 2 ft		2 to	o 3 ft		3 t	o 4 ft		4 t	o 5 ft		5 t	o 6 ft		6 t	o 7 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	1 Q2 ²															
Total Organic Carbon (percent)	_		1.780			2.320			0.463			1.640			0.691			0.510			0.047		
PCBs (µg/kg Dry-Weight)																							
Aroclor 1016	_		19	U		19	U		19	U		3.9	U		3.8	U		3.7	U		3.9	U	
Aroclor 1221	_		19	U		19	U		19	U		3.9	U		3.8	U		3.7	U		3.9	U	
Aroclor 1232	_		19	U		19	U		19	U		3.9	U		3.8	U		3.7	U		3.9	U	
Aroclor 1242	_		19	U		19	U		19	U		3.9	U		3.8	U		3.7	U		3.9	U	
Aroclor 1248	_		77	Υ	UY	58	Υ	UJ	29	Υ	UY	3.9	U		3.8	U		3.7	U		3.9	U	
Aroclor 1254	_		170			140			96			3.9	U		3.8	U		3.7	U		3.9	U	
Aroclor 1260	_		57			53			19	U		3.9	U		3.8	U		3.7	U		3.9	U	
Total PCBs 3	130		227			193			96			3.9	U		3.8	U		3.7	U		3.9	U	
Total PCBs (mg/kg-OC) 4	12		12.8			8.3			NA			0.2	U		0.5	U		0.7	U		NA	U	



PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1, 2

		Sample Location										SD-S	L4-00	6									
	Sediment	Sample Date	1/15	/2015		1/15	/2015	5	1/15	/2015		1/15	/2015		1/15	/2015	,	1/15	/2015		1/1:	5/2015	,
	Management	Sample ID	SD-SL4	-006-0	0000	SD-SL4	-006-0	0010	SD-SL4	006-00	20	SD-SL4	-006-0	030	SD-SL4	-006-0	0040	SD-SL4	-006-0	050	SD-SL4	-006-0)060
	Standards	Sample Interval	0 t	o 1 ft		1 to	o 2 ft		2 to	3 ft		3 to	o 4 ft		4 t	o 5 ft		5 to	o 6 ft		6 t	o 7 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 1	Q2 ²	Value	Q1 ¹	Q2 ²									
Total Organic Carbon (percent)	_		0.658			0.184			0.061			0.064			0.255			0.296			0.587		
PCBs (µg/kg Dry-Weight)																							
Aroclor 1016	_		20	U		3.7	U		3.8	U		3.8	U		3.8	U		3.8	U		3.8	U	
Aroclor 1221	_		20	U		3.7	U		3.8	U		3.8	U		3.8	U		3.8	U		3.8	U	
Aroclor 1232	_		20	U		3.7	U		3.8	J		3.8	U										
Aroclor 1242	_		20	U		3.7	U		3.8	U		3.8	U		3.8	U		3.8	U		3.8	U	
Aroclor 1248	_		20	U		3.7	U		3.8	J		3.8	U										
Aroclor 1254	_		53			5.5			3.8	U		3.8	U		3.8	U		3.8	U		3.8	U	
Aroclor 1260	_		20	U		3.7	U		3.8	U		3.8	U		3.8	U		3.8	U		3.8	U	
Total PCBs 3	130		53			5.5			3.8	U		3.8	U		3.8	U		3.8	U		3.8	U	
Total PCBs (mg/kg-OC) 4	12		8.1			NA			NA			NA			NA			NA			0.6	U	



PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1,2

		Sample Location													SD-S	L4-007											
	Sediment	Sample Date	1/15	/2015		1/15/	/2015	5	1/1	5/2015	5	1/15	/2015		1/15	/2015		1/15	/2015	1/1	5/201	5	1/15	/2015	5	1/15	/2015
	Management	Sample ID	SD-SL4	-007-0	0000	SD-SL4-	007-0	0010	SD-SL	4-007-	0020	SD-SL4	-007-003	30	SD-SL4	007-00	40	SD-SL4	-007-0050	SD-SL4	1-007-	-0060	SD-SL4	-007-0	0070	SD-SL4	-007-0080
	Standards	Sample Interval	0 to	o 1 ft		1 to	2 ft		2	to 3 ft		3 t	o 4 ft		4 to	5 ft		5 to	o 6 ft	6 1	to 7 ft	<u> </u>	7 t	o 8 ft		8 to	o 9 ft
Analyte	SQS		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1	1 Q2 ²	Value	Q1 ¹ C	Q2 ²	Value	Q1 1	Q2 ²	Value	Q1 ¹ Q2	² Value	Q1	1 Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹ Q2 ²
Total Organic Carbon (percent)	_		1.580			1.150			0.240			0.171			1.220			1.200		1.480			0.869			0.525	
PCBs (µg/kg Dry-Weight)																											
Aroclor 1016	_		3.9	U		3.8	U		3.8	U		3.8	U		4	U		3.8	U	3.9	U		3.9	U		3.8	U
Aroclor 1221	_		3.9	U		3.8	J		3.8	U		3.8	U		4	U		3.8	U	3.9	U		3.9	U		3.8	U
Aroclor 1232	_		3.9	U		3.8	J		3.8	U		3.8	U		4	U		3.8	U	3.9	U		3.9	U		3.8	U
Aroclor 1242	_		3.9	U		3.8	U		3.8	U		3.8	U		4	U		3.8	U	3.9	U		3.9	U		3.8	U
Aroclor 1248	_		13	Р	J	3.8	U		3.8	U		3.8	U		4	U		3.8	U	3.9	U		3.9	U		3.8	U
Aroclor 1254	_		25			3.8	U		3.8	U		3.8	U		4	U		3.8	U	3.9	U		3.9	U		3.8	U
Aroclor 1260	_		4.7			3.8	U		3.8	U		3.8	U		4	U		3.8	U	3.9	U		3.9	U		3.8	U
Total PCBs 3	130		42.7		J	3.8	U		3.8	U		3.8	U		4	U		3.8	U	3.9	U		3.9	U		3.8	U
Total PCBs (mg/kg-OC) 4	12		2.7		J	0.3	U		NA			NA			0.3	U		0.3	U	0.3	U		0.4	U		0.7	U



PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1,2

		Sample Location												SD-SI	-4-008											
	Sediment	Sample Date	1/15	/2015		1/15	/2015		1/15	/2015		1/15/	/2015		1/15	/2015		1/15	/2015		1/15	/2015		1/15	/2015	
	Management	Sample ID	SD-SL4-	008-0	000	SD-SL4-	-008-0	010	SD-SL4	-008-0	020	SD-SL4-	-008-0	030	SD-SL4-	008-0	040	SD-SL4-	-008-0	050	SD-SL4-	-008-00	060	SD-SL4	-008-0	070
	Standards	Sample Interval	0 to	1 ft		1 to	2 ft		2 t	o 3 ft		3 tc	4 ft		4 to	5 ft		5 to	o 6 ft		6 to	7 ft		7 to	o 8 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²
Total Organic Carbon (percent)	_		0.250			0.202			0.409			1.890			0.888			0.450			1.810			1.320		
PCBs (µg/kg Dry-Weight)																										
Aroclor 1016	_		3.8	U		19	U		3.9	U		20	U		19	U		20	U		3.8	U		3.9	U	
Aroclor 1221	_		3.8	U		19	U		3.9	U		20	U		19	U		20	U		3.8	U		3.9	U	
Aroclor 1232	_		3.8	U		19	U		3.9	U		20	U		19	U		20	U		3.8	U		3.9	U	
Aroclor 1242	_		3.8	U		19	U		3.9	U		20	U		19	U		20	U		3.8	U		3.9	U	
Aroclor 1248	_		21			72	Р	J	53			350	Р	J	110			40	Р	J	32			3.9	U	
Aroclor 1254	_		42			200			110			380			170			91			75			3.9	U	
Aroclor 1260	_		10			61			29			91			78			41			16			3.9	U	
Total PCBs 3	130		73			333		J	192			821		J	358			172		J	123			3.9	U	
Total PCBs (mg/kg-OC) ⁴	12		NA			NA			NA			43		J	40			NA			6.8			0.3	U	



PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1,2

		Sample Location													SD-S	L4-009	9										
	Sediment	Sample Date	1/14	1/2015	5	1/14/	/2015	5	1/1	4/2015	5	1/14	/2015		1/14	/2015		1/14	/2015	1/1	4/201	5	1/14	1/2015	5	1/14	/2015
	Management	Sample ID	SD-SL4	-009-	0000	SD-SL4-	009-0	0010	SD-SL4	4-009-	0020	SD-SL4	-009-003	30	SD-SL4-	009-0	040	SD-SL4	-009-0050	SD-SL4	l-009-	0060	SD-SL4	-009-0	0070	SD-SL4	-009-0080
	Standards	Sample Interval	0 to	o 1 ft		1 to	2 ft		2	to 3 ft		3 to	o 4 ft		4 to	5 ft		5 t	o 6 ft	6 t	o 7 ft	1	7 t	o 8 ft		8 t	o 9 ft
Analyte	sqs		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1	1 Q2 ²	Value	Q1 ¹ Q	22 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹ Q2 ²	Value	Q1	1 Q2 ²	Value	Q1 ¹	1 Q2 ²	Value	Q1 ¹ Q2 ²
Total Organic Carbon (percent)			2.350			1.110			1.040			2.580			1.620			1.190		1.530			1.050			0.083	
PCBs (µg/kg Dry-Weight)																											
Aroclor 1016	_		4	U		3.8	U		3.8	U		3.8	U		3.9	U		3.9	U	3.8	U		3.8	U		3.9	U
Aroclor 1221			4	U		3.8	J		3.8	U		3.8	U		3.9	U		3.9	U	3.8	U		3.8	U		3.9	U
Aroclor 1232			4	U		3.8	J		3.8	U		3.8	U		3.9	U		3.9	U	3.8	U		3.8	U		3.9	U
Aroclor 1242			4	U		3.8	U		3.8	U		3.8	U		3.9	U		3.9	U	3.8	U		3.8	U		3.9	U
Aroclor 1248			85			260			240			480			600			1200		1300			660			3.9	U
Aroclor 1254	_		130			760			680			1800			1700			3200		3800			1900			3.9	U
Aroclor 1260			37			110			140			230			270			470		590			280			3.9	U
Total PCBs 3	130		252			1130			1060			2510			2570			4870		5690		·	2840		·	3.9	U
Total PCBs (mg/kg-OC) 4	12		10.7			102			102			97			159			409		372			270			NA	



PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1,2

		Sample Location										SD-S	L4-01	0									
	Sediment	Sample Date	1/14	/2015	,	1/14	1/2015		1/14	/2015	5	1/14	/2015		1/14	1/2015	,	1/14	1/2015		1/1	4/2015	,
	Management	Sample ID	SD-SL4	-010-0	0000	SD-SL4	-010-0	010	SD-SL4	-010-0	0020	SD-SL4	-010-0	030	SD-SL4	-010-0	0040	SD-SL4	-010-0	050	SD-SL4	-010-0	060
	Standards	Sample Interval	0 t	o 1 ft		1 t	o 2 ft		2 to	3 ft		3 t	o 4 ft		4 t	o 5 ft		5 t	o 6 ft		6 t	to 7 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²																		
Total Organic Carbon (percent)	_		0.653			0.717			3.130			1.200			0.462			0.048		J	0.880		J
PCBs (µg/kg Dry-Weight)																							
Aroclor 1016	_		3.9	U		4	U		4	U		3.8	U		4	U		3.9	U		3.8	U	
Aroclor 1221	_		3.9	U		4	U		4	U		3.8	U		4	U		3.9	U		3.8	U	
Aroclor 1232	_		3.9	U		4	U		4	U		3.8	U		4	U		3.9	U		3.8	U	
Aroclor 1242	_		3.9	U		4	U		4	U		3.8	U		4	U		3.9	U		3.8	U	
Aroclor 1248	_		5.8	Υ	UY	4	U		4	U		3.8	U		4	U		3.9	U		3.8	U	
Aroclor 1254	_		16			12			4	U		3.8	U		4	U		3.9	U		3.8	U	
Aroclor 1260	_		5			4	U		4	U		3.8	U		4	U		3.9	U		3.8	U	
Total PCBs 3	130		21			12			4	U		3.8	U	·	4	U	·	3.9	U		3.8	U	
Total PCBs (mg/kg-OC) 4	12		3.2			1.7			0.1	U		0.3	U		NA			NA			0.4	U	UJ



PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1, 2

		Sample Location														SE)-SL	4-011													
	Sediment	Sample Date		4/201	5	1/1	4/201	5	1/1	4/201	5	1/1	4/201	5	1/14	1/2015		1/14/	2015	1/1	4/201	5	1/1	4/201	5	1/1	4/2015	5	1/1	4/2015	;
	Management	Sample ID	SD-SL	4-011-	0000	SD-SL4	4-011-	0010	SD-SL	4-011-	0020	SD-SL4	4 - 011	-0030	SD-SL4	-011-00	40	SD-SL4-	011-0050	SD-SL	4-011-	0060	SD-SL	4-011	-0070	SD-SL	4-011-	0800	SD-SL4	4-011-0)090
	Standards	Sample Interval	0	to 1 ft	:	1	to 2 ft	:	2	to 3 ft		3	to 4 ft	t	4 t	o 5 ft		5 to	6 ft	6	to 7 ft	:	7	to 8 f	i	8	to 9 ft	:	9 t	o 10 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 1 Q	2 ²	Value	Q1 ¹ Q2	² Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²	Value	Q1 ¹	Q2 ²
Total Organic Carbon (percent)			3.080		J	2.820		J	0.808		J	1.610		J	1.720		J	1.080	J	1.000		J	0.385		J	0.990		J	0.216		J
PCBs (µg/kg Dry-Weight)																															
Aroclor 1016	_		19	U		19	U		19	U		62	U		39	U		20 L	J	3.8	U		3.8	U		3.9	U		3.9	U	
Aroclor 1221			19	U		19	U		19	U		62	U		39	U		20 L	J	3.8	U		3.8	U		3.9	U		3.9	U	
Aroclor 1232			19	U		19	U		19	U		62	U		39	U		20 L	J	3.8	U		3.8	U		3.9	U		3.9	U	
Aroclor 1242			19	U		19	U		19	U		62	U		39	U		20 L	J	3.8	U		3.8	U		3.9	U		3.9	U	
Aroclor 1248	_		58			69			55			870			1300			740		14			3.8	U		3.9	U		3.9	U	
Aroclor 1254			88			110			190			2500			3500			2000		38			3.8	U		3.9	U		3.9	U	
Aroclor 1260			45			51			40			400			550			320		7.8			3.8	U		3.9	U		3.9	U	
Total PCBs 3	130		191			230			285			3770			5350			3060		59.8			3.8	U		3.9	U		3.9	U	1
Total PCBs (mg/kg-OC) 4	12		6.2		J	8.2		J	35		J	234		J	311		J	283	J	6.0		J	NA			0.4	U	UJ	NA		



PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE RESULTS 1,2

Slip 4 Additional Data Collection
Duwamish Sediment Other Area and Southwest Bank
Corrective Measure and Habitat Project
Boeing Plant 2
Seattle/Tukwila, Washington

·		Sample Location							SD-SI	L4-012	2						
	Sediment	Sample Date	1/15	/2015		1/15	/2015		1/15	/2015		1/15	/2015		1/15	/2015	
	Management	Sample ID	SD-SL4-	012-0	000	SD-SL4-	012-0	010	SD-SL4-	012-0	020	SD-SL4-	012-0	030	SD-SL4-	012-0	040
	Standards	Sample Interval	0 to	1 ft		1 to	2 ft		2 to	3 ft		3 to	4 ft		4 to	5 ft	
Analyte	sqs		Value	Q1 ¹	Q2 ²												
Total Organic Carbon (percent)	_		0.657			0.416			0.354			0.224			1.470		
PCBs (μg/kg Dry-Weight)																	
Aroclor 1016	_		19	U		3.8	U		3.9	U		3.8	U		3.7	U	
Aroclor 1221	_		19	U		3.8	U		3.9	U		3.8	U		3.7	U	
Aroclor 1232	_		19	U		3.8	U		3.9	U		3.8	U		3.7	U	
Aroclor 1242	_		19	U		3.8	U		3.9	U		3.8	U		3.7	U	
Aroclor 1248	_		62	Р	J	32			5.8	Υ	UY	3.8	U		3.7	U	
Aroclor 1254	_		98			79			18			3.8	U		3.7	U	
Aroclor 1260	_		36		J	18			3.9	U		3.8	U		3.7	U	
Total PCBs ³	130		196		J	129			18			3.8	U		3.7	U	
Total PCBs (mg/kg-OC) 4	12	·	30		J	NA			NA			NA			0.3	U	

Note(s)

- 1. Laboratory qualifiers (Q1) are defined as follows:
- U = analyte not detected at reporting limit presented.
- Y = The analyte is not detected at or above the reported concentration. The reporting limit is raised due to chromatographic interference. The Y flag is equivalent to the U flag with a raised reporting limit. P = The analyte was detected on both chromatographic corumns but the quantified values differ by >40% RPD with no obvious chromatographic interference.
- 2. Validation qualifiers (Q2) are defined as follows:
- UY = The reporting limit was elevated due to chromatographic overlap with related compounds. The material was analyzed for, but was not detected above, the level of the associated value.
- J = The analyte was positively identified. The associated numerical value is the approximate concentration of the analyte in the sample.
- UJ = The material was analyzed for, but was not detected. The associated value is an estimate and may be inaccurate or imprecise.
- 3. Total PCBs calculated by summing results for detected congeners or, if all not detected, using the highest reporting limit for non-detected congeners.
- 4. NA: Carbon outside the range for normalization (<0.5 % or >4.0%).

Abbreviation(s)

ft = feet

mg/kg-OC = milligrams per kilogram organic carbon

PCBs = polychlorinated biphenyls

RPD = relative percent difference

SQS = Sediment Management Standards Sediment Quality Standards (173-204-320 WAC)

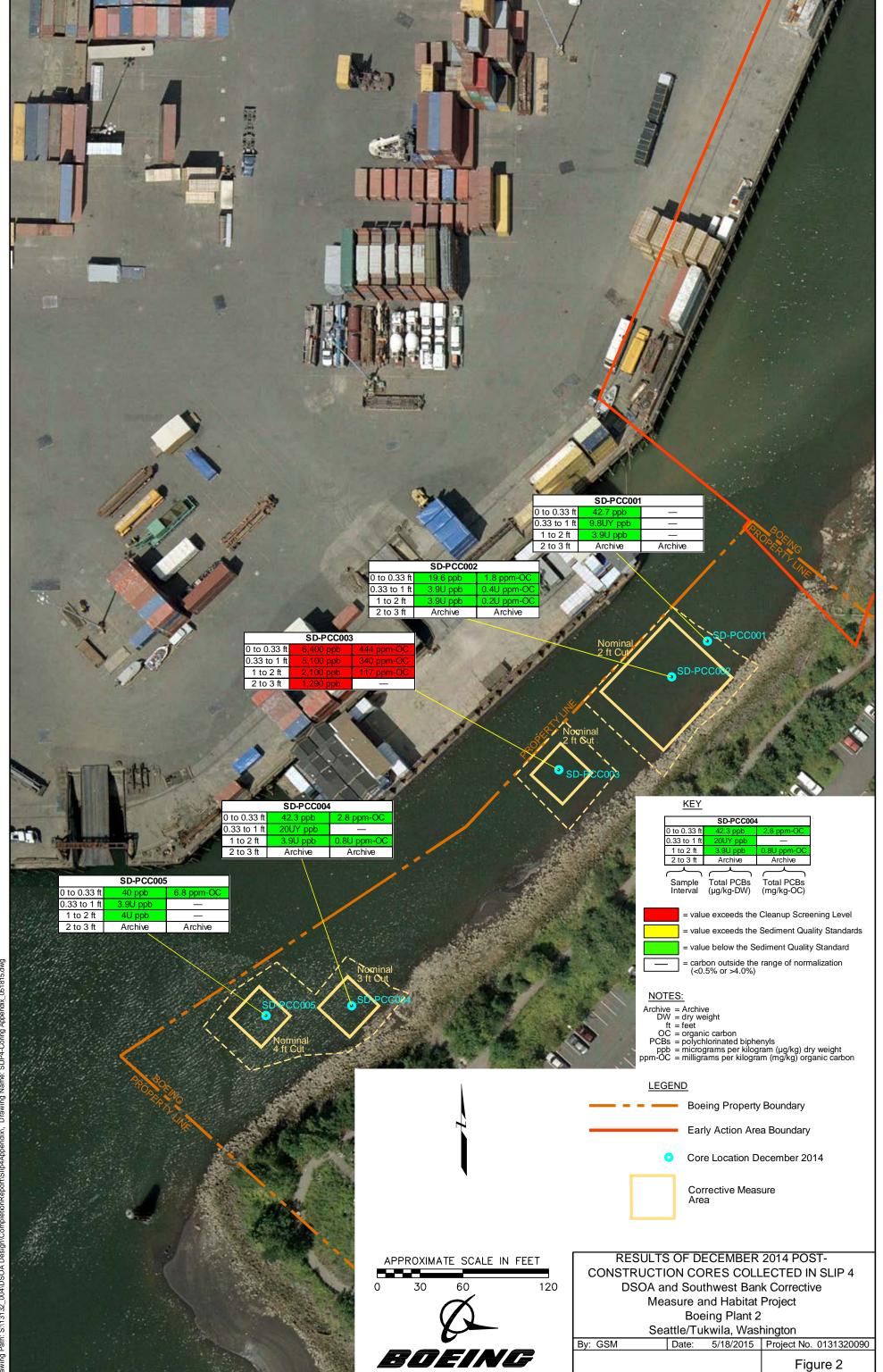
μg/kg Dry-Weight = micrograms per kilogram dry weight

WAC = Washington Administrative Code

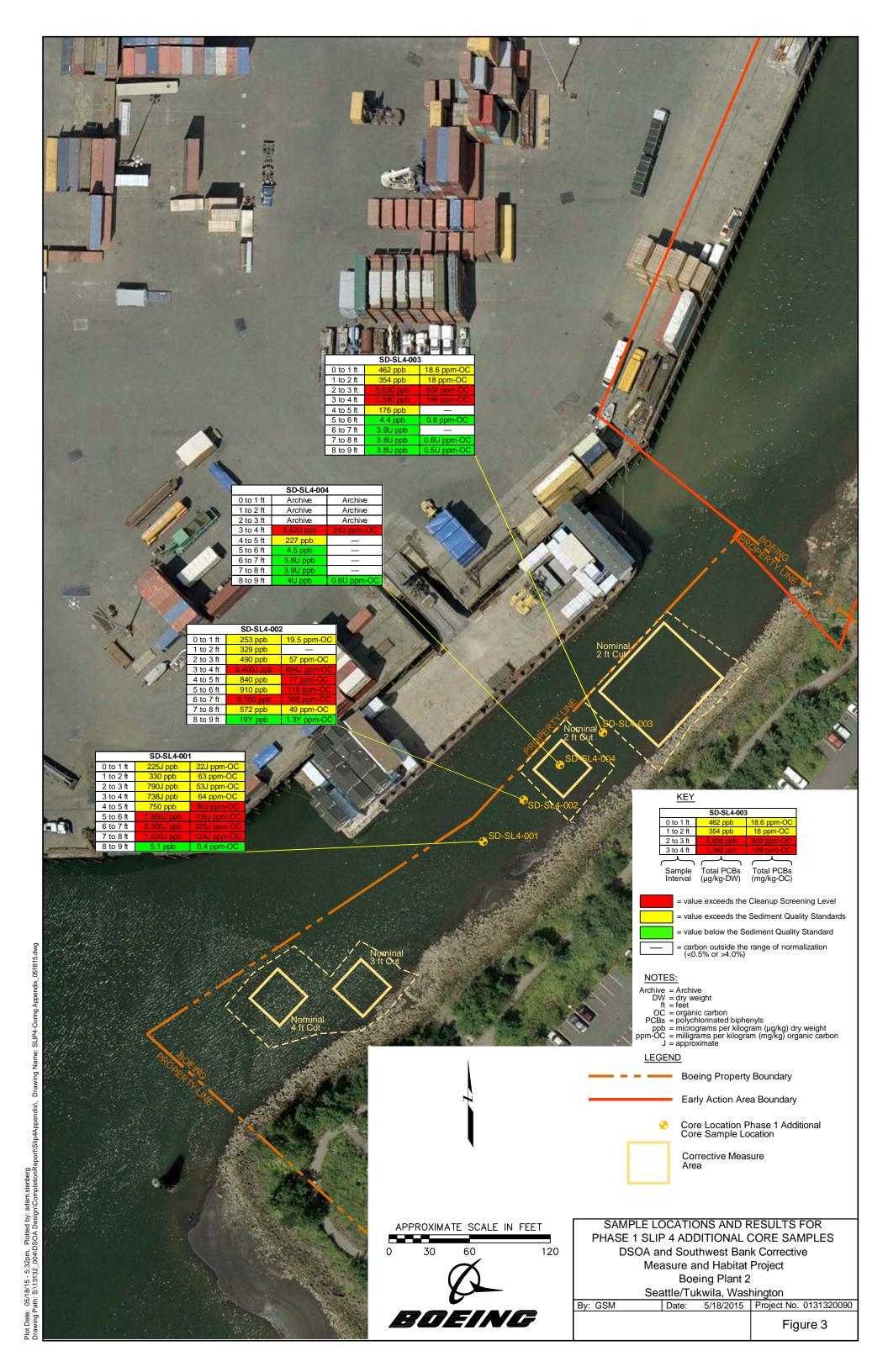


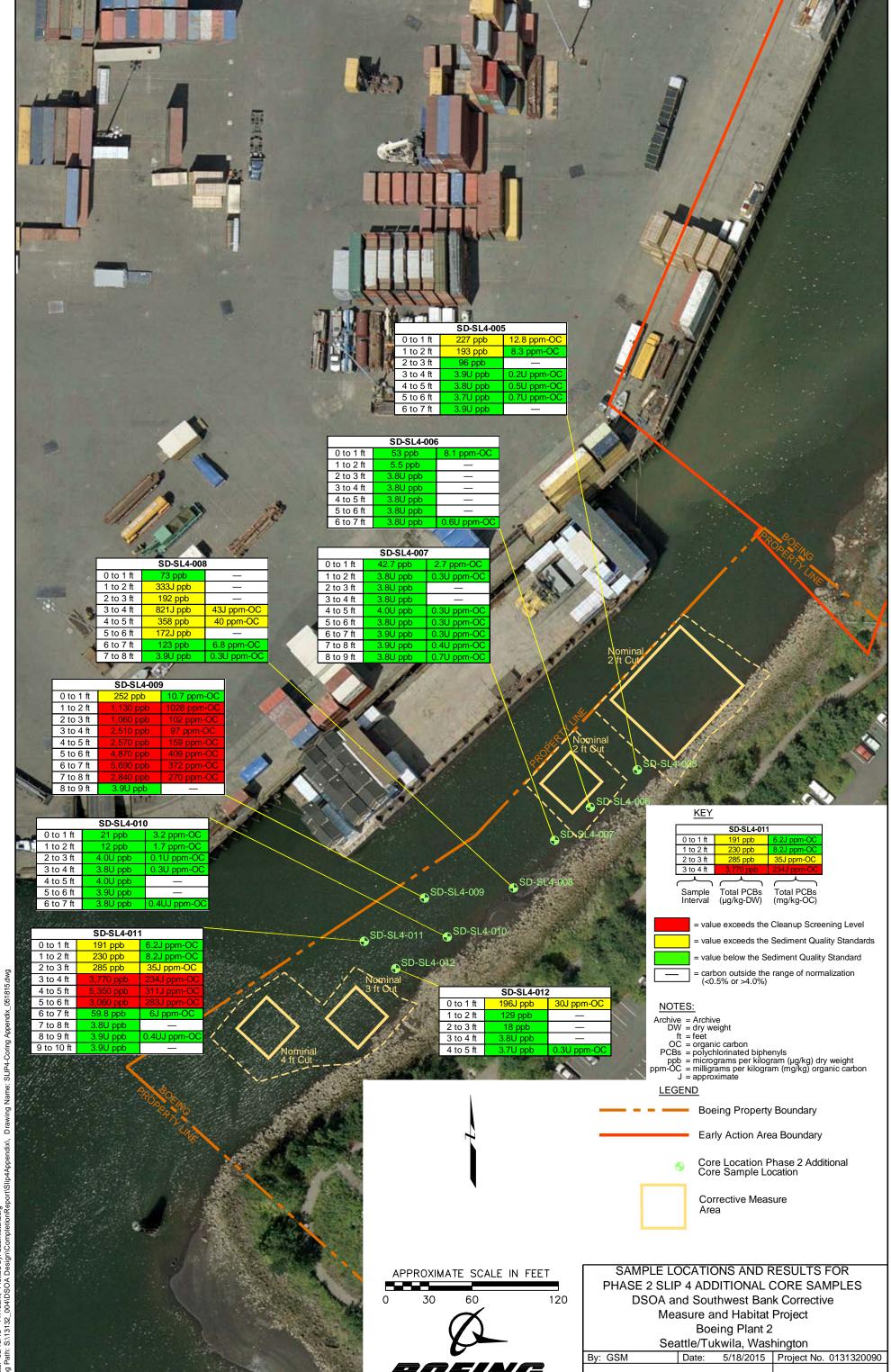
Plot Date: 05/18/15 - 5:27pm, Plotted by: adam:stenberg Drawing Path: S:\13132_004\DSOA Design\CompletionReport\Slip4Appendix\, Drawing Name: SLIP4-Coring Appendix_(

Figure 1



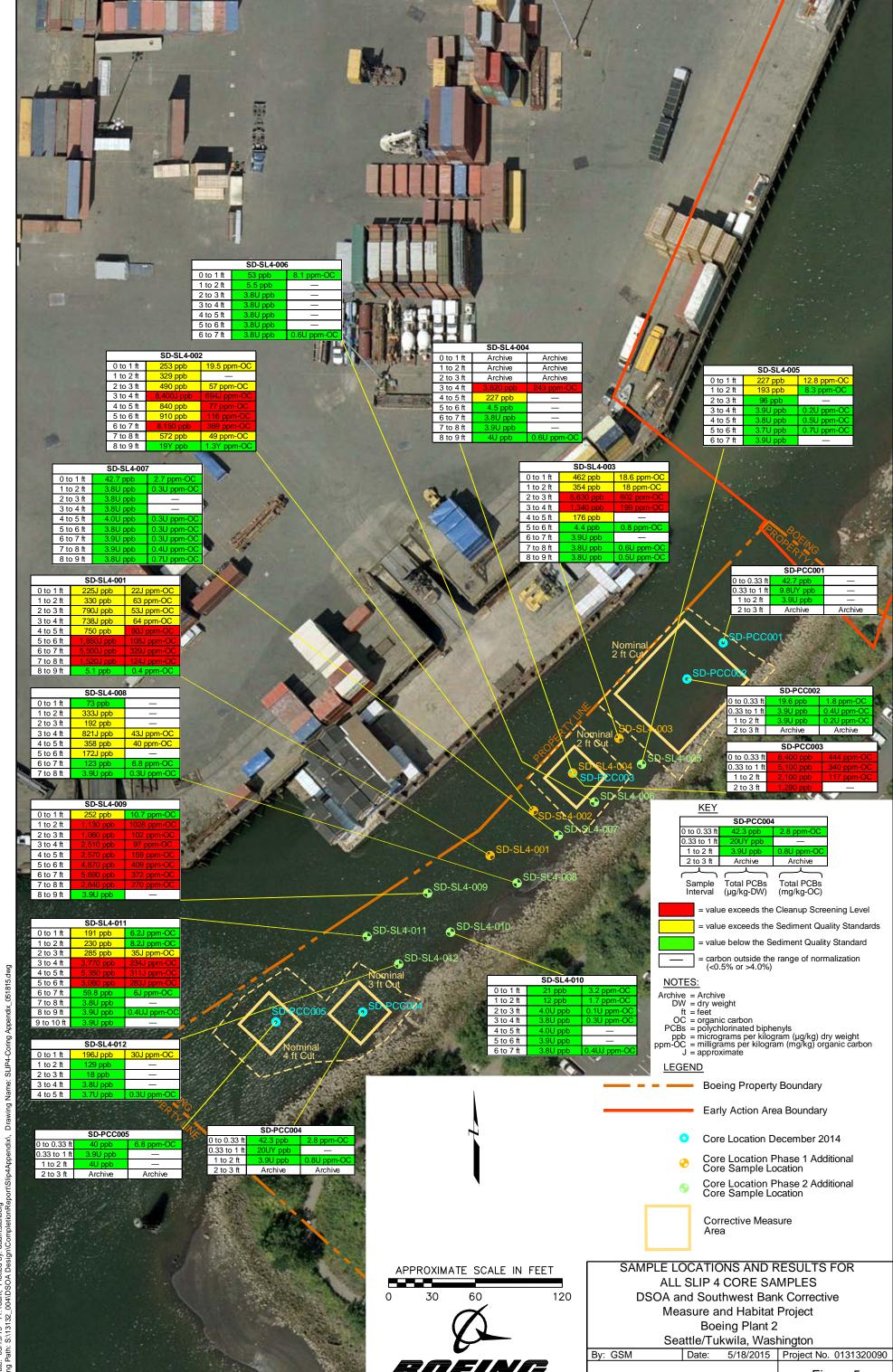
Plot Date: 05/18/15 - 5:29pm, Plotted by: adam.stenberg Drawing Path: S:\1312_004\DSOA Design\CompletionReport\Slip4Appendix\, Drawing Name: SLP4-Coring Ap





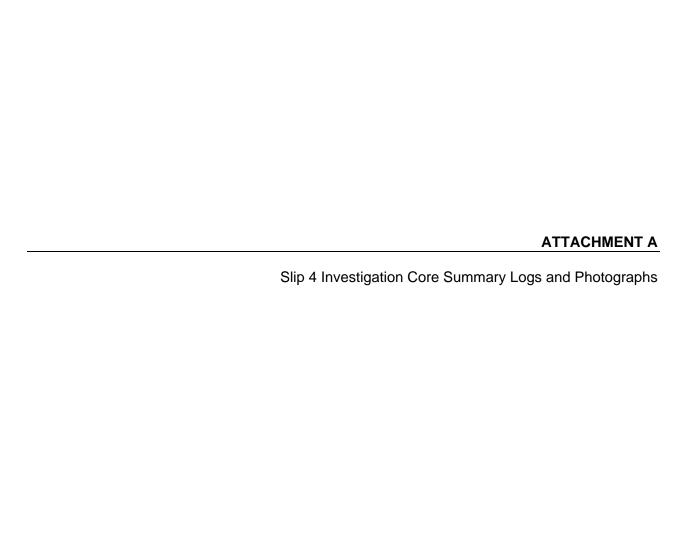
Plot Date: 05/19/15 - 11:18am, Plotted by: adam.stenberg Drawing Path: S:\13132_004\DSOA Design\CompletionReport\Slip4Appendix\, Drawing Name: SLIP4-Coring Ap

Figure 4



Plot Date: 05/19/15 - 11:16am, Plotted by: adam.stemberg Drawing Path: S/13132_004/DSOA Design/CompletionReport/Slip4Appendix/,

Figure 5





Project: BP2 PC Coring Station: SD-PCC001

Project No: 0131320090.CRMN

Maximum depth of retained sediment: 4.2 ft

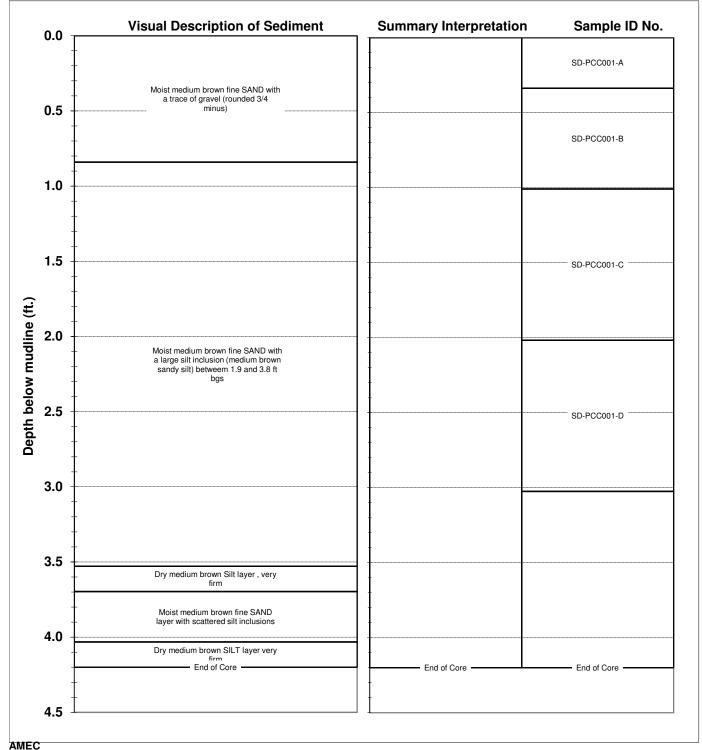
Mudline elevation: -12.2 ft MLLW

Percent recovery (on-deck): 60%

Core Laboratory collection processing

 Date:
 12/9/2014
 12/9/2014
 Field Log:
 R. Gilmour

 Time:
 12:19
 15:00
 Summary Log:
 R. Gilmour









Station: SD-PCC002 Project: BP2 PC Coring

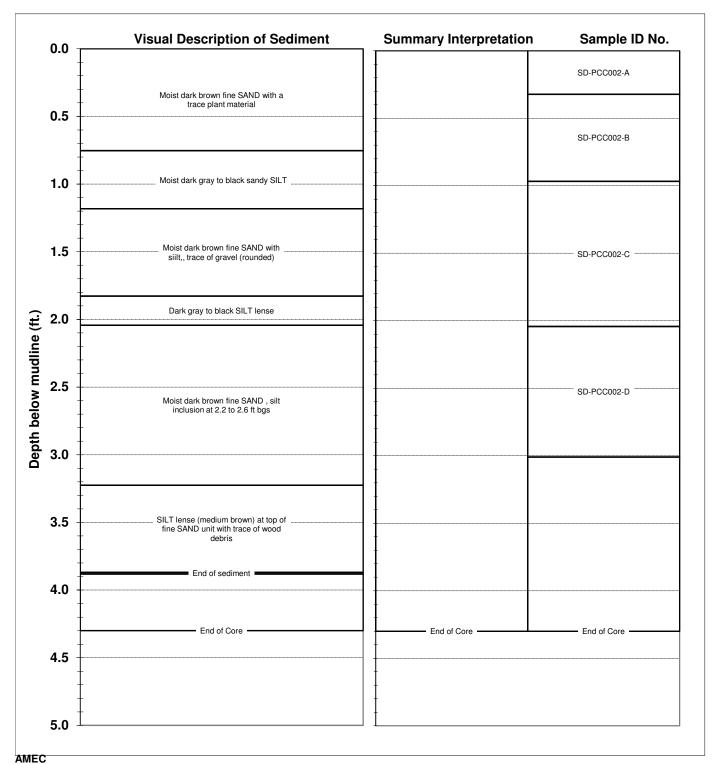
Project No: 0131320090.CRMN

Maximum depth of retained sediment:

Mudline elevation: -14.3 ft MLLW Percent recovery (on-deck): 93%

Core Laboratory collection processing

12/9/2014 12/9/2014 Field Log: R. Gilmour Date: Time: Summary Log: R. Gilmour 11:58 15:40



File name: SD-PCC002.xls Summary Core Log





Station SD-PCC002





Station: SD-PCC003 Project: BP2 PC Coring

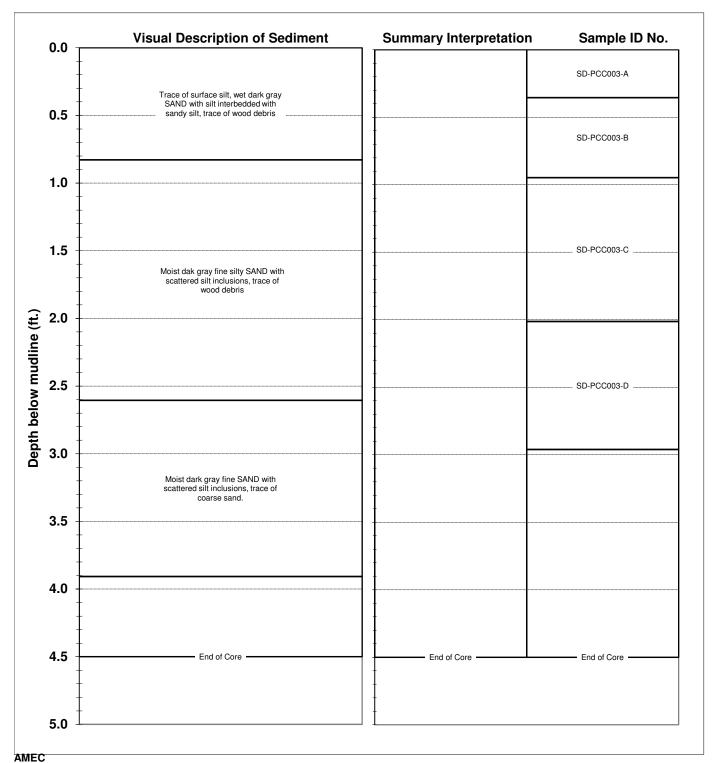
Project No: 0131320090.CRMN

Maximum depth of retained sediment:

Mudline elevation: -14.2 ft MLLW Percent recovery (on-deck):

Core Laboratory collection processing

12/8/2014 12/8/2014 Field Log: R. Gilmour Date: Time: Summary Log: R. Gilmour 11:55 13:30



File name: SD-PCC003.xls Summary Core Log





Station SD-PCC003





Station SD-PCC003

Project: BP2 PC Coring Station: SD-PCC004

Project No: 0131320090.CRMN

 $\begin{tabular}{ll} \textbf{Maximum depth of retained sediment:} & 4.7 & ft \\ \end{tabular}$

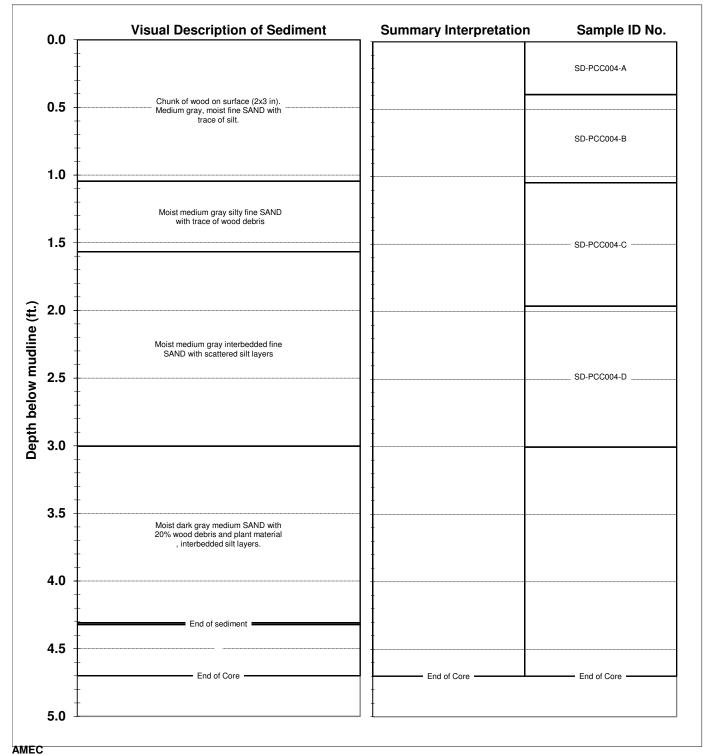
Mudline elevation: -12.6 ft MLLW

Percent recovery (on-deck): 77%

Core Laboratory collection processing

 Date:
 12/8/2014
 12/8/2014
 Field Log:
 R. Gilmour

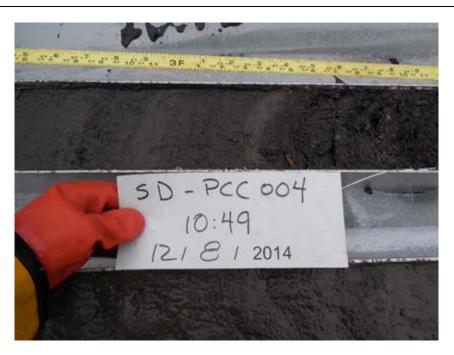
 Time:
 10:49
 15:48
 Summary Log:
 R. Gilmour

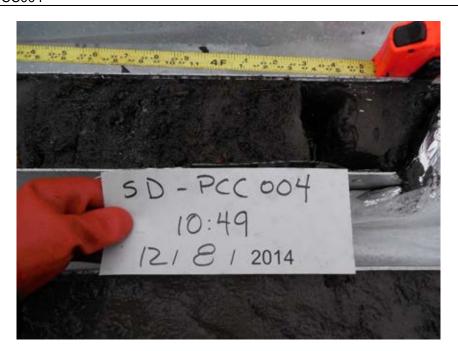






Station SD-PCC004





Station SD-PCC004

Project: BP2 PC Coring Station: SD-PCC005

Project No: 0131320090.CRMN

Maximum depth of retained sediment: 4.4 ft

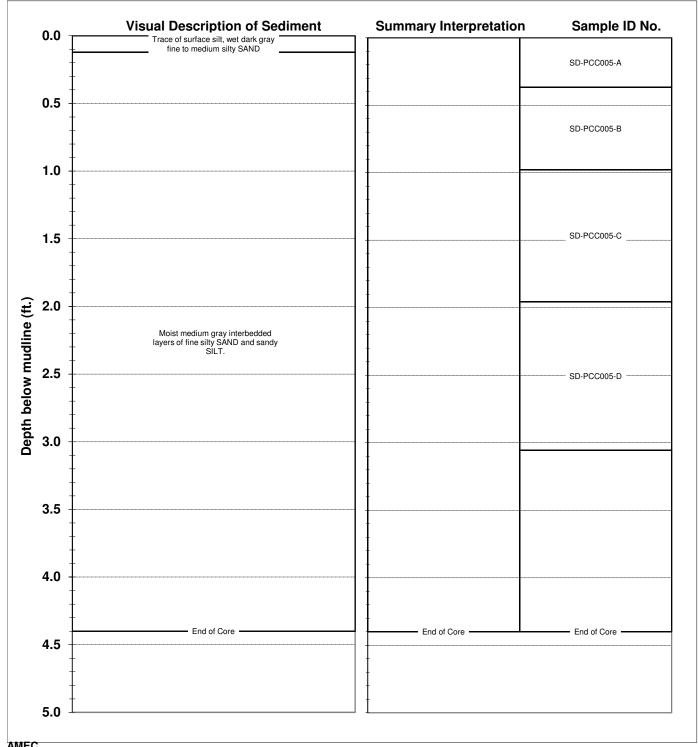
Mudline elevation: -19.7 ft MLLW

Percent recovery (on-deck): 82%

Core Laboratory collection processing

 Date:
 12/8/2014
 12/8/2014
 Field Log:
 R. Gilmour

 Time:
 11:25
 16:04
 Summary Log:
 R. Gilmour



File name: SD-PCC005.xls Summary Core Log



Station SD-PCC005



Station SD-PCC005



Station SD-PCC005



Station SD-PCC005

PHASE 1 SLIP 4 ADDITIONAL CORE SAMPLE COLLECTION

Project: BP2 Slip 4 Coring Station: SD-SL4-001

Project No: 0131320090.STMS

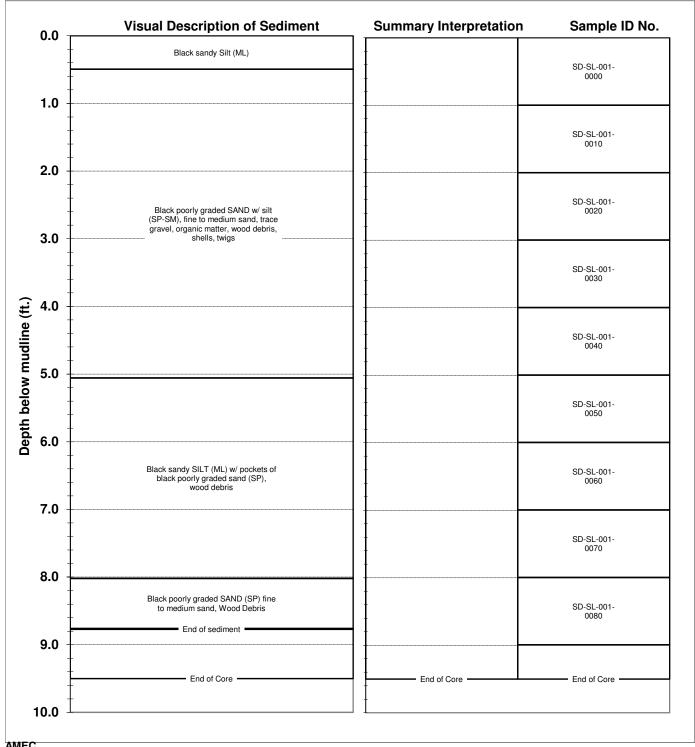
Maximum depth of retained sediment: 9.5 ft

Mudline elevation: -8.8 ft MLLW

Percent recovery (on-deck): 81%

Core Laboratory collection processing

Date:12/22/2014NAField Log:J. BellamyTime:9:50NASummary Log:R. Gilmour



File name: SL4-001.xls Summary Core Log



Station SD-SL4-001





Station SD-SL4-001





Station SD-SL4-001





Station SD-SL4-001





Station SD-SL4-001



Project: BP2 Slip 4 Coring Station: SD-SL4-002

Project No: 0131320090.STMS

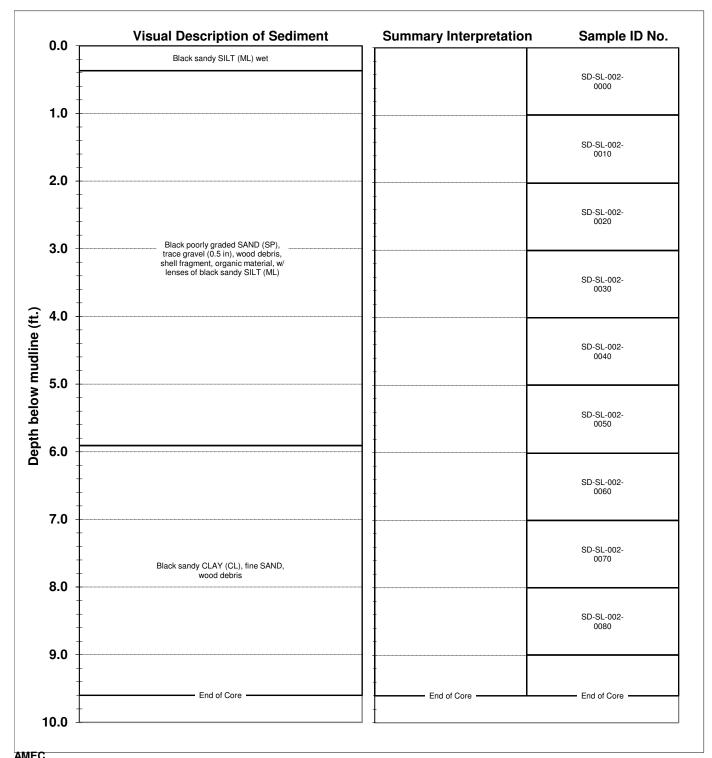
Maximum depth of retained sediment: 9.6 ft

Mudline elevation: -9.1 ft MLLW

Percent recovery (on-deck): 81%

Core Laboratory collection processing

Date:12/22/2014NAField Log:J. BellamyTime:10:19NASummary Log:R. Gilmour



File name: SL4-002.xls Summary Core Log



Station SD-SL4-002



Station SD-SL4-002



Station SD-SL4-002





Station SD-SL4-002









Station SD-SL4-002



Station: SD-SL4-003 Project: BP2 Slip 4 Coring

Project No: 0131320090.STMS

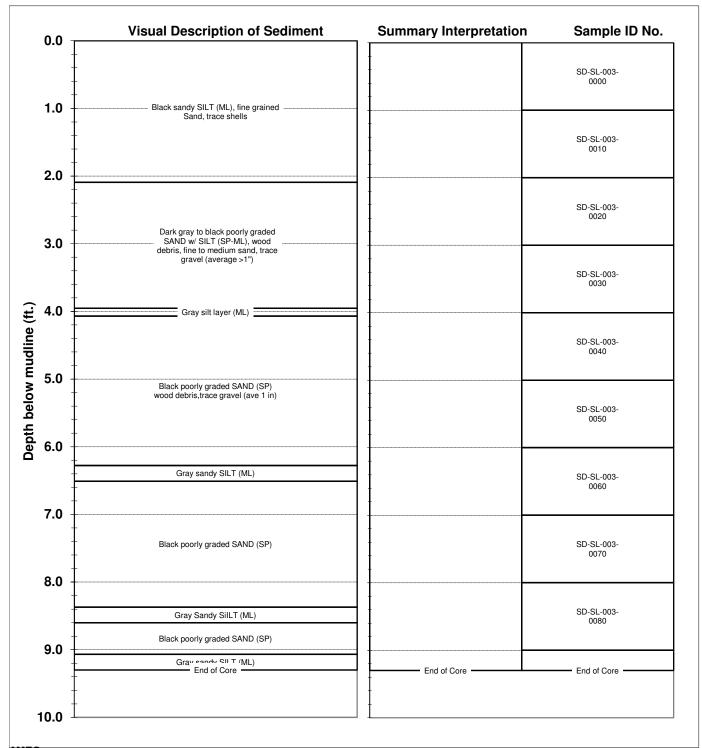
Maximum depth of retained sediment: 9.3

-10.3 ft MLLW Mudline elevation:

Percent recovery (on-deck): 86%

Core Laboratory collection processing

12/22/2014 Field Log: J. Bellamy Date: N/A Summary Log: R. Gilmour Time: 11:24 N/A





Station SD-SL4-003



Station SD-SL4-003



Station SD-SL4-003



Station SD-SL4-003



Station SD-SL4-003





Station SD-SL4-003



Station SD-SL4-003



Station SD-SL4-003



Station SD-SL4-003



Station SD-SL4-003



Station SD-SL4-003

Station: SD-SL4-004 Project: BP2 Slip 4 Coring

Project No: 0131320090.STMS

Maximum depth of retained sediment:

Mudline elevation: -13.7 **ft MLLW** Percent recovery (on-deck): 63%

Core Laboratory collection processing

Date: 12/22/2014 NA Field Log: J. Bellamy Summary Log: R. Gilmour Time: NA 10:49

0.0	Visual Description of Sediment	Summary Interpretation	Sample ID No
† †	Black sandy SILT (ML), wet, trace wood debris		SD-SL-004- 0000
1.0			SD-SL-004- 0010
2.0	Black poorly graded SAND (SP), fin eto coarse Sand, trace wood debris, leaves		
3.0			SD-SL-004- 0020
10	Black sandy CLAY (CL)	-	SD-SL-004- 0030
4.0			SD-SL-004- 0040
5.0	Plack poorly graded SAND (SD) fine		SD-SL-004-
6.0	Black poorly graded SAND (SP) fine to medium SAND		0050
			SD-SL-004- 0060
7.0	Gray sandy SILT (ML) interbedded with black poorly graded SAND (SP)		SD-SL-004- 0070
8.0			SD-SL-004-
9.0	Gray sandy SILT (ML) trace wood debris		0080
	Black poorly graded SAND (SP), fine to medium sand End of Core	End of Core	End of Core
ـــــ 0.0 ا		J <u> </u>	

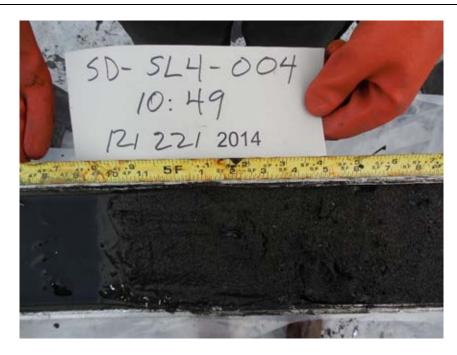
File name: SL4-004.xls Summary Core Log



Station SD-SL4-004



Station SD-SL4-004







Station SD-SL4-004



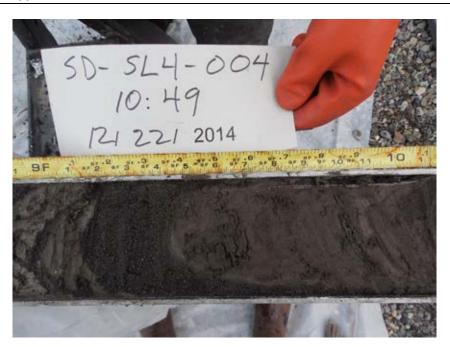


Station SD-SL4-004





Station SD-SL4-004





PHASE 2 SLIP 4 ADDITIONAL CORE SAMPLE COLLECTION

Project: BP2 Slip 4 Coring Station: SD-SL4-005

Project No: 0131320090.STMS

Maximum depth of retained sediment: 7.3 ft

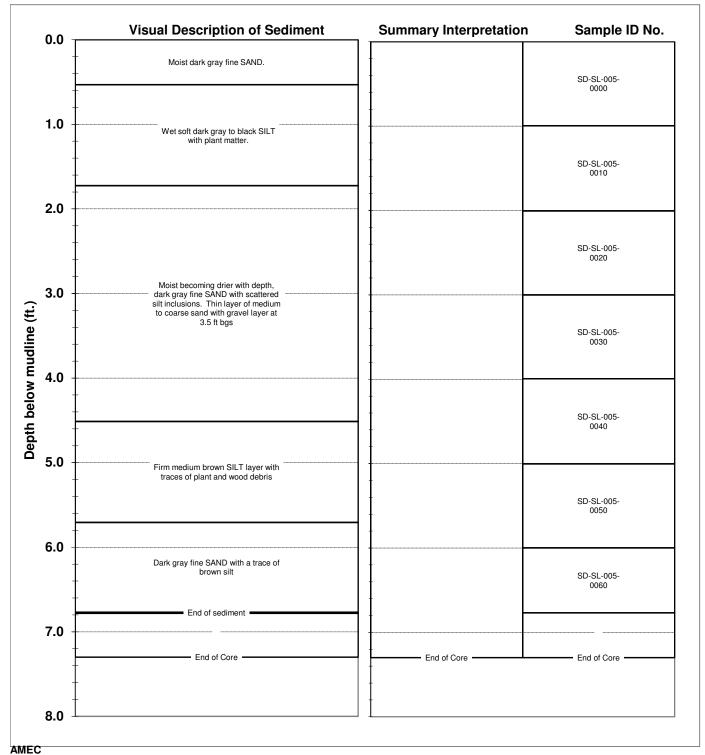
Mudline elevation: -6.5 ft MLLW

Percent recovery (on-deck): 75%

Core Laboratory collection processing

 Date:
 1/15/2015
 Field Log:
 R. Gilmour

 Time:
 10:28
 15:05
 Summary Log:
 R. Gilmour



File name: SD_SL4-005.xls Summary Core Log



Station SD-SL4-005



Station SD-SL4-005



Station SD-SL4-005



Station SD-SL4-005



Station SD-SL4-005



Station SD-SL4-005



Station SD-SL4-005

Project: BP2 Slip 4 Coring Station: SD-SL4-006

Project No: 0131320090.STMS

Maximum depth of retained sediment: 6.7 ft

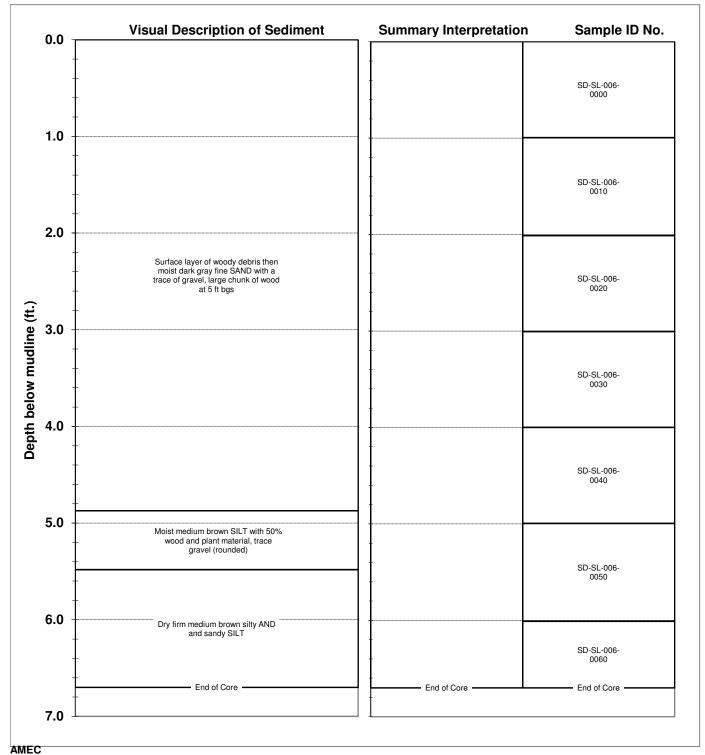
Mudline elevation: -7.5 ft MLLW

Percent recovery (on-deck): 49%

Core Laboratory collection processing

 Date:
 1/15/2015
 1/15/2015
 Field Log:
 R. Gilmour

 Time:
 9:52
 15:30
 Summary Log:
 R. Gilmour



File name: SD_SL4-006.xls Summary Core Log



Station SD-SL4-006



Station SD-SL4-006



Station SD-SL4-006



Station SD-SL4-006



Station SD-SL4-006

Station: SD-SL4-007 Project: BP2 Slip 4 Coring

Project No: 0131320090.STMS

Maximum depth of retained sediment:

Mudline elevation: -5.2 ft MLLW Percent recovery (on-deck): 78%

Laboratory Core collection processing

Date: 1/15/2015 1/15/2015 Field Log: R. Gilmour Summary Log: R. Gilmour Time: 15:50 9:27

0.0	Visual Description of Sediment Wet dark gray silty SAND with	Summary Interpretation	Sample ID No
‡	gravel	_	SD-SL-007-
+	Dark gray to black sandy SILT with a trace of plant material		0000
1.0	а насе отрининателна		
	Medium brown silty fine SAND,		SD-SL-007- 0010
2.0	section of branch at top of interval (unstained)		20.0
1			SD-SL-007- 0020
3.0	Dark gray fine SAND, scattered pieces of reddish brick at 2.8 to 3.2		
1	pieces of reddish brick at 2.8 to 3.2 ft bgs, trace of coarse sand.		SD-SL-007- 0030
4.0			
-			
			SD-SL-007- 0040
5.0			
	Medium brown silty fine SAND with		SD-SL-007- 0050
6.0	trace of wood and plant material, some interbedding at bottom of interval		
			SD-SL-007-
+			0060
7.0			
		1	SD-SL-007- 0070
8.0			
+	Interbedded layers of fine silty SAND and sandy SILT, piece of		SD-SL-007-
+	wood at 7.8 ft bgs.		0080
9.0			
+	End of Core	End of Core	End of Core
0.0			

File name: SD_SL4-007.xls Summary Core Log



Station SD-SL4-007



Station SD-SL4-007



Station SD-SL4-007



Station SD-SL4-007



Station SD-SL4-007



Station SD-SL4-007



Station SD-SL4-007



Station SD-SL4-007



Station SD-SL4-007



Station SD-SL4-007

Station: SD-SL4-008 Project: BP2 Slip 4 Coring

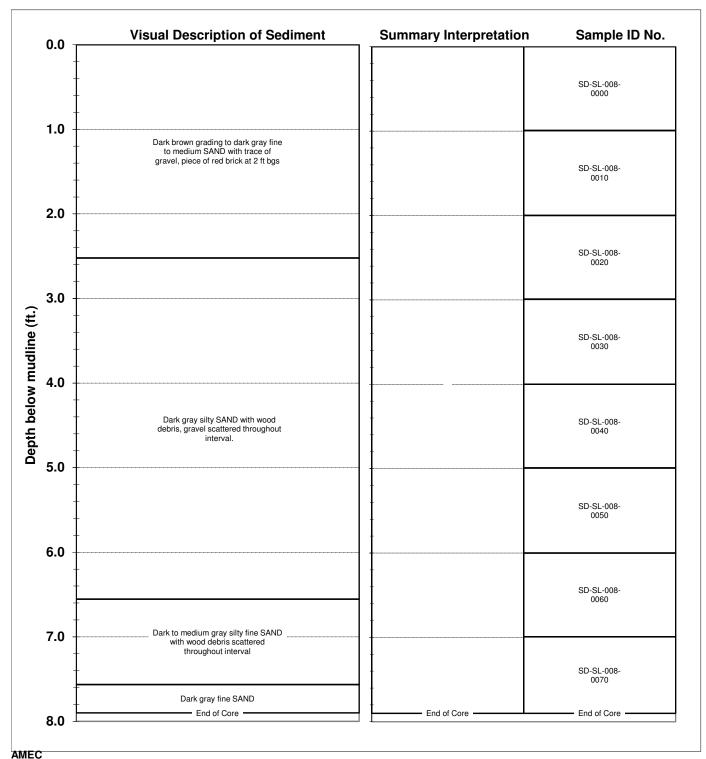
Project No: 0131320090.STMS

Maximum depth of retained sediment:

Mudline elevation: -3.3 ft MLLW Percent recovery (on-deck): 59%

Core Laboratory collection processing

1/15/2015 Date: 1/15/2015 Field Log: R. Gilmour Summary Log: R. Gilmour Time: 11:20 16:45





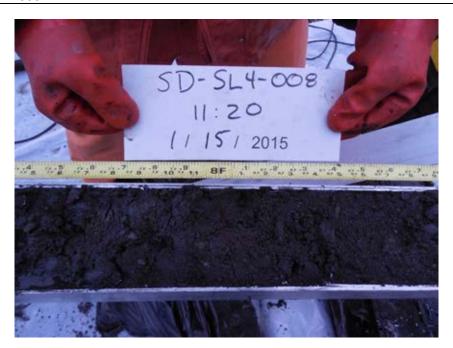
Station SD-SL4-008



Station SD-SL4-008



Station SD-SL4-008



Station SD-SL4-008



Station SD-SL4-008



Station SD-SL4-008



Station SD-SL4-008

Station: SD-SL4-009 Project: BP2 Slip 4 Coring

Project No: 0131320090.STMS

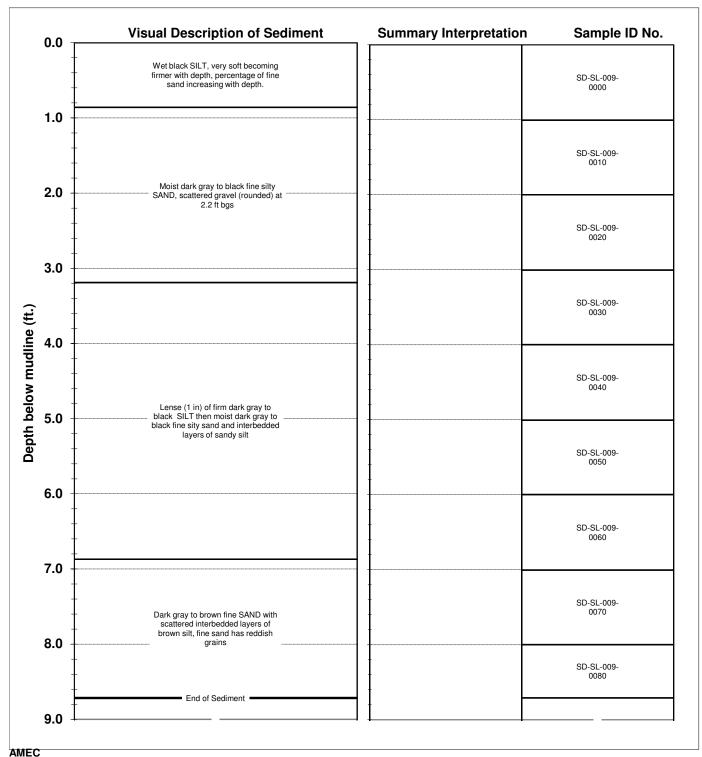
Maximum depth of retained sediment: 9.2

-10.0 ft MLLW Mudline elevation:

Percent recovery (on-deck): 82%

Core Laboratory collection processing

1/14/2015 Date: N/A Field Log: R. Gilmour Summary Log: R. Gilmour Time: 11:46 N/A



File name: SD_SL4-009.xls Summary Core Log



Station SD-SL4-009





Station SD-SL4-009





Station SD-SL4-009



Station SD-SL4-009



Station SD-SL4-009



Station SD-SL4-009





Project: BP2 Slip 4 Coring Station: SD-SL4-010

Project No: 0131320090.STMS

Maximum depth of retained sediment: 8.2 ft

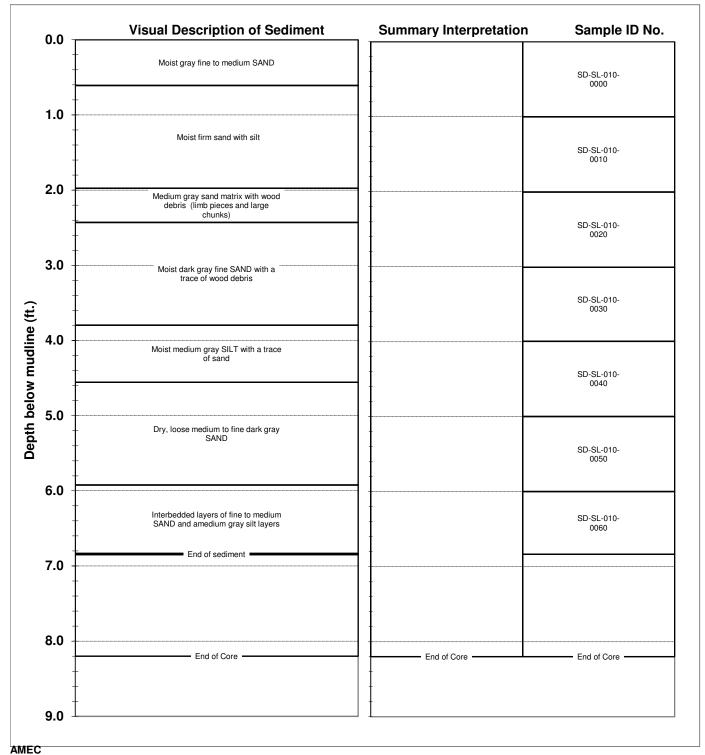
Mudline elevation: -4.3 ft MLLW

Percent recovery (on-deck): 66%

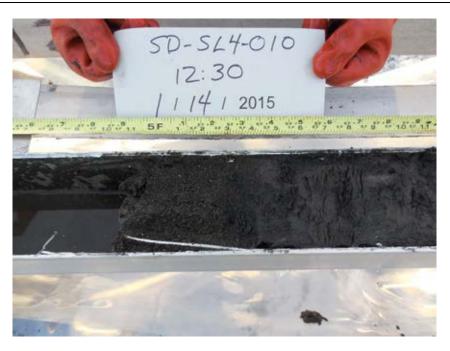
Core Laboratory collection processing

 Date:
 1/14/2015
 1/14/2015
 Field Log:
 R. Gilmour

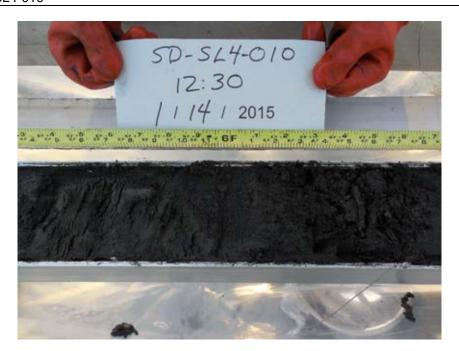
 Time:
 12:30
 16:15
 Summary Log:
 R. Gilmour



File name: SD_SL4-010.xls Summary Core Log



Station SD-SL4-010



Station SD-SL4-010



Station SD-SL4-010



Station SD-SL4-010



Station SD-SL4-010



Station SD-SL4-010



Station SD-SL4-010

Core Summary Log

Station: SD-SL4-011 Project: BP2 Slip 4 Coring

Project No: 0131320090.STMS

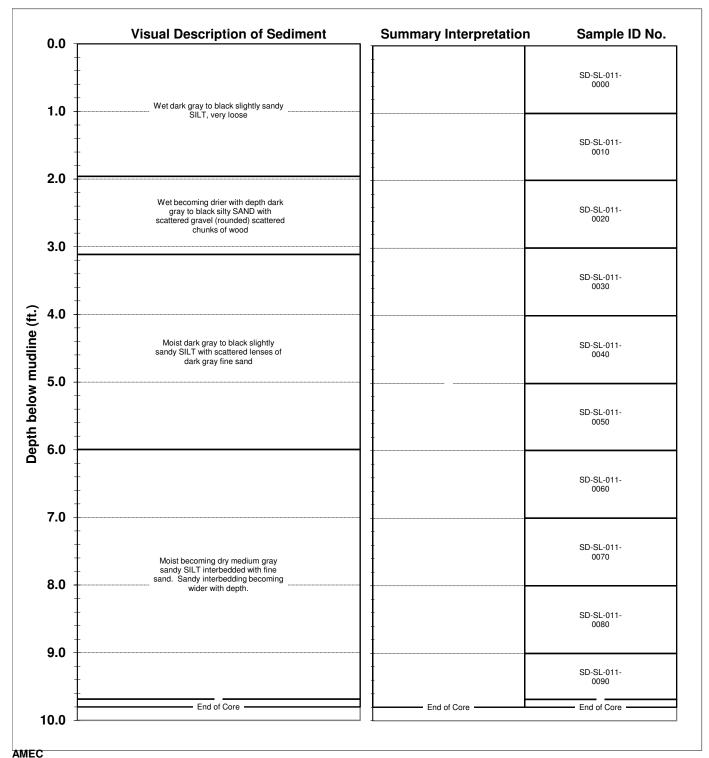
Maximum depth of retained sediment: 9.8

-10.9 ft MLLW Mudline elevation:

Percent recovery (on-deck): 87%

Core Laboratory collection processing

1/14/2015 1/14/2015 Date: Field Log: R. Gilmour Summary Log: R. Gilmour Time: 11:11 15:35



File name: SD_SL4-011.xls Summary Core Log



Station SD-SL4-011



Station SD-SL4-011



Station SD-SL4-011



Station SD-SL4-011



Station SD-SL4-011



Station SD-SL4-011



Station SD-SL4-011



Station SD-SL4-011



Station SD-SL4-011



Station SD-SL4-011



Station SD-SL4-011

Core Summary Log

Project: BP2 Slip 4 Coring Station: SD-SL4-012

Project No: 0131320090.STMS

Maximum depth of retained sediment: 5.3 ft

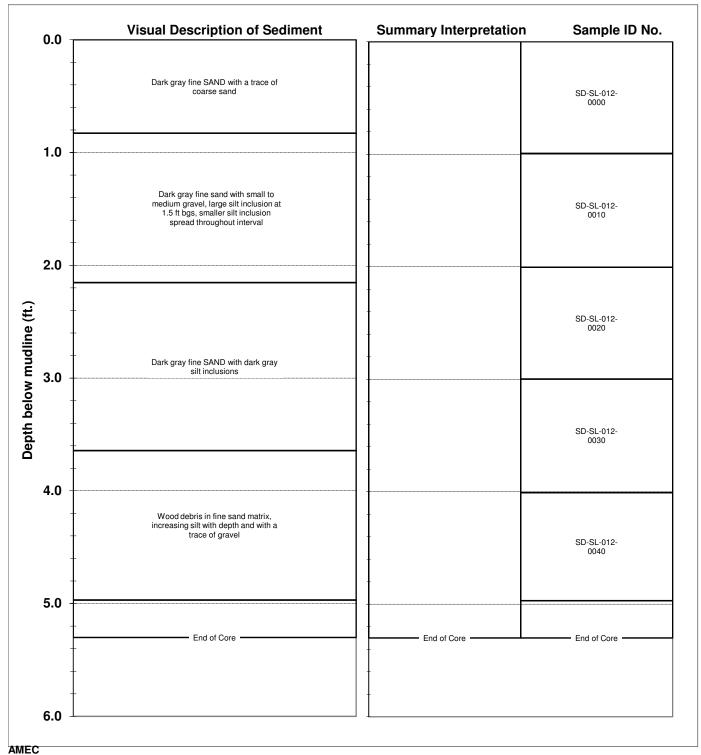
Mudline elevation: -7.2 ft MLLW

Percent recovery (on-deck): 60%

Core Laboratory collection processing

 Date:
 1/15/2015
 1/15/2015
 Field Log:
 R. Gilmour

 Time:
 12:49
 16:15
 Summary Log:
 R. Gilmour



File name: SD-SL4-012 r2.xls Summary Core Log



Station SD-SL4-012



Station SD-SL4-012



Station SD-SL4-012



Station SD-SL4-012

	_
ATTACHMENT	R
ALIAOLIMENT	_

Chain-of-Custody Forms

3500 188th St. SW. Suite 601 Lynnwood,WA 98037 (425) 921-4000

CHAIN OF CUSTODY

		Anal	ysis Containers		
Place Sample ID Label Here or Write ID Number Here		SMS Metals (As, Cd, Cr, Cu, Pb, Hg, Ag, Zn) TOC, and PCBs (by Aroclor)	Archive		Recorded by:
AMEC: BP2 PCC Sampling	Date:				Number of containers
SD-PCC003-A					
COC Form	Time:				
Date: 121 8 1 14 Time: 1/55 AMEC: BP2 PCC Sampling	Date:	-			Number of containers
SD-PCC003-B					
COC Form	Time:	$\dashv \times \vdash$		1	
Date: 1218 119 Time: 1155					
AMEC: BP2 PCC Sampling	Date:				Number of containers
SD-PCC003-C		,		1	
COC Form	Time:	$\dashv \times \mid$	1	1	
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SD-PCC003-D	Date.		37	1	
COC Form	Time:	_	\times		
Date: 1218 119 Time: 1155 AMEC: BP2 PCC Sampling					Number of containers
SD-PCC004-A	Date:			. 1	Hombor of containers
COC Form		\perp			
Date: 12/8/14 Time: 1049	Time:				
AMEC: BP2 PCC Sampling					Number of containers
SD-PCC004-B	Date:				Transport of containers
COC Form		\rightarrow			
Date: 12/8/19 Time: 1049	Time:				
AMEC: BP2 PCC Sampling	0.10				Number of containers
SD-PCC004-C	Date:				
COC Form	Time	-			
	Time:				
Date: 12 / 5 14 Time: 1049					
Laboratory Sample Keceipt	200	Relir Name:	equished By	Name:	Received By

ARI Project Manager—Kelly Bottem

AMEC Project Manager—Cliff Whitmus (cliff.whitmus@amec.com.ph.
425-921-4023)

AMEC Laboratory Coordinator—Crystal Neirby
(crystal.neirby@amec.com.ph. 206-838-8469)

Sediment samples are unhomogenized. Samples must be thoroughly homogenized before analysis.

Relinquished By	Received By
Name: Calmor	Name:
Date: (2/8/14	Date: 12 & .161
Time: 1655	Time: 11 5 5

Admin\Field Forms\COC

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CHAIN OF CUSTODY

		Ana	alysis Containe	ers	
Place Sample ID Label Here or Write ID Number Here AMEC: BP2 PCC Sampling		SMS Metals (As, Cd, Cr, Cu, Pb, Hg, Ag, Zn) TOC, and PCBs (by Aroclor)	Archive		Recorded by:
SD-PCC004-D	Date:				Number of containers
COC Form			3.3		
Y and the second of the second	Time;		X		
Date: 121 8 1 14 Time: 1049			2 80		
AMEC: BP2 PCC Sampling	Date:				Number of containers
SD-PCC005-A					
COC Form	Time:	$\neg \times \mid$			
Date: 12 8 1 44 Time: 1125					
AMEC: BP2 PCC Sampling	Date:				Number of containers
SD-PCC005-B					
COC Form	Time	\neg \checkmark			
Date: 12 1 8 1 14 Time: 11 25					
AMEC: BP2 PCC Sampling	Date:				Number of containers
SD-PCC005-C					
COC Form	Time:	$ \times$ $ $			
Date: 1218114 Time: 1125					
AIVIEL: BP2 PCC Sampling	Date:				Number of containers
SD-PCC005-D			7		
COC Form	Time:		*		
Date: 1218 114 Time: 1125					
	Date:				Number of containers
Place Sample ID Label Here or Write ID Number Here					
	Time:				
Dissa Samala 10 Lakel Hass	Date:				Number of containers
Place Sample 1D Label Here or Write ID Number Here					
	Time:				
Laboratory Sample Receipt			uished By		Received By
ARI Project Manager—Kelly Bottem AMEC Project Manager—Cliff Whitmus (cliff whitmus@amec.com.ph		Name:	Elm	Name:	72
425-921-4023) AMEC Laboratory Coordinator—Crystal Neirby		Date:	11	Date:	7 / 10
(crystal.neirby@amec.com ph. 206-838-8469)		Time:	18/14	Time:	Z. G. 11;
Sediment samples are unhomogenized. Samples must be thorought homogenized before analysis	y		55	Time.	155

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CHAIN OF CUSTODY

	91.150	Anal	ysis Containers	
Place Sample ID Label Here or Write ID Number Here		SMS Metals (As, Cd, Cr, Cu, Pb, Hg, Ag, Zn) TOC, and PCBs (by Aroclor)	Archive	Recorded by:
AMEC: BP2 PCC Sampling	Date			Number of containers
SD-PCC001-A				
COC Form	Time:			<i>j</i>
Date: 129 19 Time: 1219				
AMEC: BP2 PCC Sampling	Date:			Number of containers
SD-PCC001-B		1		
COC Form	Time:			
Date: 12 9 14 Time: 12 9 AMEC: BP2 PCC Sampling	Date:			Number of containers
SD-PCC001-C			- 4	Number of containers
COC Form	Time:	- 1		-
Date: 121 9 114 Time: 1219				,
AMEC: BP2 PCC Sampling	Date:	+		Number of containers
SD-PCC001-D				
COC Form	Time:	-		
Date: 12 19 124 Time: 1219 AMEC: BP2 PCC Sampling			1	
SD-PCC002-A	Date:			Number of containers
COC Form				
Date: 12 1 9 1 19 Time: 158	Time:	/		1
AMEC: BP2 PCC Sampling	Date:	-		Number of containers
SD-PCC002-B				
COC Form	Time:	/		
Date: 1219 119 Time: 11589			į.	1
AMEC: BP2 PCC Sampling	Date:			Number of containers
SD-PCC002-C				, some of containing
COC Form	Time:	— X		
Date: 12 9 14 Time: 1138				<i>)</i>
Laboratory Sample Receipt		Relinqui		Received By
		Name: 1	- N - N	Name:

ARI Project Manager—Kelly Bottem

AMEC Project Manager—Cliff Whitmus (cliff whitmus@amec.com ph
425-921-4023)

AMEC Laboratory Coordinator—Crystal Neirby
(crystal.neirby@amec.com ph. 206-838-8469)

Sediment samples are unhomogenized. Samples must be thoroughly homogenized before analysis.

Relinquished By	Received By
Name: Calmore	Name:
Date: 12/9/14	Date:
Time: / 4 3 0	Time:

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	-	Ana	lysis Container:	S	
Place Sample ID Label Here or Write ID Number Here		SMS Metals (As, Cd, Cr, Cu, Pb, Hg, Ag, Zn) TOC, and PCBs (by Aroclor)	Archive		Recorded by:
AMEC: BP2 PCC Sampling	Date:				Number of containers
SD-PCC002-D			1		
COC Form	Time:	† I	X		1
Date: 12 1 9 1 14 Time: 1158		1 1	2000		I
F	Date:	+		-	Number of containers
Place Sample ID Label Here or Write ID Number Here				1	realities of contasters
	Time:	7 1			
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	Time:	1 1			
	Date:	+			Number of containers
Place Sample ID Label Here or Write ID Number Here					
	Time:				
Place Sample ID Label Here or Write ID Number Here	Date:				Number of containers
	Time:				
	Date:	+			Number of containers
Place Sample ID Label Here or Write ID Number Here					0.0000000000000000000000000000000000000
	Time;				
Place Sample ID Label Here or Write ID Number Here	Date:				Number of containers
	Time:	1			ì
				1	
Laboratory Sample Receipt		Relinqui	sheri Ru		Descript D.
ARI Project Manager—Kelly Bottern		Name:	/	Name:	Received By
AMEC Project Manager—Cliff Whitmus (cliff.whilmus@amec.com.ph 425-921-4023)			africie	6	
AMEC Laboratory Coordinator—Crystal Neirby (crystal neirby@amec.com_ph. 206-838-8469)		Date: / 2/	9/14	Date:	12/9/14
Sediment samples are unhomogenized. Samples must be thoroughly homogenized before analysis.	(14:	36	Time:	e30
					Admin\Field Forms\COC

Sediment samples are unhomogenized. Samples must be thoroughly homogenized before analysis.

Analysis Containers Place Sample ID Label Here PCBs (by Aroclor) Recorded by: _____ or Write ID Number Here Checked by: and TOC AMEC: Slip 4 Sampling Date: Number of containers SD-SL4-001-0000 COC Form Time: Date: 12/22 /14 Time: 950 AMEC: Slip 4 Sampling Date: Number of containers SD-SL4-001-0010 Time: COC Form Date: 12/ 32/14 Time: 956 AMEC: Slip 4 Sampling Date: Number of containers SD-SL4-001-0020 COC Form Time: Date: 12/ 22/14 Time: 950 Date: AMEC: Slip 4 Sampling Number of containers SD-SL4-001-0030 Time: COC Form Date: 12/ 22/14 Time: 950 AMEC: Slip 4 Sampling Date: Number of containers SD-SL4-001-0040 Time: COC Form Date: 12/ 22/14 Time: 950 AMEC: Slip 4 Sampling Date: Number of containers SD-SL4-001-0050 COC Form Time: Date: 12/22/14 Time: 950 AMEC: Slip 4 Sampling Date: Number of containers SD-SL4-001-0060 COC Form Time: Date: 12/ [2]/14 Time: 950 Laboratory Sample Receipt Relinquished By Received By Name: Name: ARI Project Manager-Kelly Bottem AMEC Project Manager-Cliff Whitmus (cliff.whitmus@amec.com.ph 120 trunk 425-921-4023) Date: Date: AMEC Laboratory Coordinator—Crystal Neirby (crystal.neirby@amec.com ph. 206-838-8469)

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		Anal	ysis Containe	rs	
Place Sample ID Label Here or Write ID Number Here		PCBs (by Aroclor) and TOC	Archive		Recorded by:
AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-001-0070					
COC Form	Time:				1
Date: 12/22/14 Time: 950 AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-001-0080					19
COC Form	Time:		1	1	7
Date: 12/ 22/14 Time: 950				TOTAL I CONTRACTOR OF THE PARTY	
AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-002-0000			1		
COC Form	Time:	1			1
Date: 12/22 /14 Time: AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-002-0010	Time:	_			į.
COC Form	1				
Date: 12/72/14 Time: /2/6 +	: Date:				Number of containers
SD-SL4-002-0020	Time:				4
COC Form					
Date: 12/ 2 2 /14 Time: / 0 / 9 = AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-002-0030	Time:	- \			1
COC Form	S.	\			
Date: 12/23/14 Time: 10:19 AMEC: Slip 4 Sampling	Date:	1			Number of containers
SD-SL4-002-0040		- / ·			/
COC Form	Time:				
Date: 12/22/14 Time: 10/19					
ARI Project Manager—Kelly Bottem AMEC Project Manager—Cliff Whitmus (cliff.whitmus@amec.com ph 425-921-4023) AMEC Laboratory Coordinator—Crystal Neirby (crystal.neirby@amec.com ph. 206-838-8469) Sediment samples are unhomogenized. Samples must be thoroughl homogenized before analysis.	У	Name: 2(-) Date: 12-/	lished By Lymen 22/14 45	Date:	Received By

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Sediment samples are unhomogenized. Samples must be thoroughly homogenized before analysis.

CHAIN OF CUSTODY

	- processing	Ana	lysis Containers	
Place Sample ID Label Here or Write ID Number Here		PCBs (by Aroclor) and TOC	Archive	Recorded by:
AMEC: Slip 4 Sampling	Date.			Number of containers
SD-SL4-002-0050				
COC Form	Time:			1
Date: 12/2 <u>2</u> /14 Time: // /9 AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-002-0060				
COC Form	Time:			6
Date: 12/22_/14 Time: /2/9 AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-002-0070			1	
COC Form	Time:	N I		1
Date: 12/22 /14 Time: / 6/9 AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-002-0080		4 1		
COC Form	Time:			t.
Date: 12/ 22 /14 Time: /2/9 AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-003-0000				
COC Form	Time:	7		1
Date: 12/ 22 /14 Time: //2 // AMEC: Slip 4 Sampling	Date;			Number of containers
SD-SL4-003-0010	Time:	- 7		1
COC Form				
Date: 12/22/14 Time: //2 // AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-003-0020	Time;	1]
COC Form	Talle.			
Date: 12/_22/14 Time:_//29/				
ARI Project Manager—Kelly Bottem		Name:	shed By	Received By
AMEC Project Manager—Cliff Whitmus (cliff.whitmus@amec.co 425-921-4023) AMEC Laboratory Coordinator—Crystal Neirby (crystal.neirby@amec.com_ph. 206-838-8469)	m ph	Date:	1. Hara	Date:

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AWEC 3500 188th St. SW, Suite 601 Lynnwood,WA 98037 (425) 921-4000

CHAIN OF CUSTODY

	paramounts	Anal	ysis Containers	
Place Sample ID Label Here or Write ID Number Here		PCBs (by Aroclor) and TOC	Archive	Recorded by:
AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-003-0030				
COC Form	Time:		ľ	<i>t</i>
Date: 12/ 22/14 Time: #24/ AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-003-0040				
COC Form	Time:	V		X
Date: 12/2 /14 Time: 1/2 // AMEC: Slip 4 Sampling	Date:	-		Number of containers
SD-SL4-003-0050				
COC Form	Time:			7
Date: 12/22/14 Time: 124 AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-003-0060				Trained of Containers
COC Form	Time:	- \		
Date: 12/ 77 /14 Time: 177 / AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-003-0070				
COC Form	Time:			#
Date: 12/22/14 Time: 1/29				
AMEC: Slip 4 Sampling	Date:			Number of containers
SD-SL4-003-0080				
COC Form	Time:	× 1		
Date: 12/22/14 Time: // 2 7	Della			
Place Sample ID Label Here or Write ID Number Here	Date:			Number of containers
	Time:			
Laboratory Sample Receipt		Relinqu	uished By	Received By

_	Euroratory Campie Necesipt	
ARI P	Project Manager—Kelly Bottem	
AME	C Project Manager—Cliff Whitmus (cliff.whitmus@amec.com.ph	
425-9	921-4023)	
AME	C Laboratory Coordinator—Crystal Neirby	
(cryst	stal.neirby@amec.com ph. 206-838-8469)	
Sed	diment samples are unhomogenized. Samples must be thoroughly	
	homogenized before analysis.	

Relinquished By	Received By
Name:	Name:
Canara	
Date:	Date:
12/22/14	12/22/14
Time:	Time:
16:45	164

AMEC 3500 188th St. SW, Suite 601 Lynnwood,WA 98037 (425) 921-4000

CHAIN OF CUSTODY

	orbination (C.	Ana	ilysis Containe	ers	
Place Sample ID Label Here or Write ID Number Here		PCBs (by Aroclor) and TOC	Archive		Recorded by:
AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-004-0000					
COC Form	Time:	7			, i
Date: 12/27/14 Time: 1347 AMEC: Slip 4 Sampling	Date:	-			Number of containers
SD-SL4-004-0010					
COC Form	Time:		X		/
Date: 12/ 7 2 /14 Time: 12/9 AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-004-0020					
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AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-004-0030					
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Date: 12/ 3 2 /14 Time: 10 4 9 AMEC: Slip 4 Sampling	Date:	-			Number of containers
SD-SL4-004-0040					
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Date: 12/ 72/14 Time: 1049 AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-004-0050					
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Date: 12/ 2 2 /14 Time: 70 4/50 AMEC: Slip 4 Sampling	Date:				Number of containers
SD-SL4-004-0060		1			1
COC Form	Time:	×			*
Date: 12/12_/14 Time: 1649					
Laboratory Sample Receipt	9	Name:	quished By	Name:	Received By
ARI Project Manager—Kelly Bottem AMFC Project Manager—Cliff Whitmus (cliff,whitmus@amec.cc)	om ph	Name.	12 m	/ Name.	1

ARI Project Manager—Kelly Bottem

AMEC Project Manager—Cliff Whitmus (cliff.whitmus@amec.com ph
425-921-4023)

AMEC Laboratory Coordinator—Crystal Neirby
(crystal.neirby@amec.com ph. 206-838-8469)

Sediment samples are unhomogenized. Samples must be thoroughly
homogenized before analysis.

Relinquished by	Received By	
Name:	Name:	Ī
1 Commen	C	
Date: 12/22/14	Date: 1.2/20/10/	
Time: 1245	Time: //4 <	

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homogenized before analysis.

CHAIN OF CUSTODY

(425) 921-4000		Analysis Containers	
Place Sample ID Label Here or Write ID Number Here		PCBs (by Aroclor)	Recorded by:
		PCBs (by Archive	Checked by:
AMEC: Slip 4 Sampling	Date:	1	Number of containers
SD-SL4-005-0000			
COC Form	Time;	$\dashv \times \mid \; \mid \; \mid$.4
Date: 1//15 Time: AMEC: Slip 4 Sampling	Date:		Number of containers
SD-SL4-005-0010			
COC Form	Time	T X 1	
Date: 1//15 Time: AMEC: Slip 4 Sampling	Date:		Number of containers
SD-SL4-005-0020		1 / 1	1
COC Form	Time:		
Date: 1/ /15 Time: AMEC: Slip 4 Sampling	Date		Number of containers
SD-SL4-005-0030			1
COC Form	Time:	T X	1
AMEC: Slip 4 Sampling	- Date:		Number of containers
SD-SL4-005-0040			
COC Form	Time:		
Date: 1//15 Time:			
AMEC: Slip 4 Sampling	Date:		Number of containers
SD-SL4-005-0050	Time.	1 X 1 1	1
COC Form	Time.		
Date: 1//15 Time: AMEC: Slip 4 Sampling	Dale:		Number of containers
SD-SL4-005-0060			
COC Form	Time:		
Date: 1//15 Time:			
RI Project Manager—Kelly Bottem		Relinquished By	Received By
MEC Project Manager—Nerly Bottem MEC Project Manager—Cliff Whitmus (cliff, whitmus@amec.com.pl 25-921-4023)	h	Kathan	1
MHEC Laboratory Coordinator—Crystal Neirby crystal neirby@amec.com ph. 206-838-8469)		Date:	Date:
Sediment samples are unthomogenized. Samples must be thorough	hlv	Time: (//3//3	Time:

----3500 188th St. SW, Suite 601 Lynnwood,WA 98037 (425) 921-4000

CHAIN OF CUSTODY

		Ana	lysis Containers	
Place Sample ID Label Here or Write ID Number Here		PCBs (by Aroclor) and TOC	Archive	Recorded by:
AMEC: Slip 4 Sampling	Date			Number of containers
SD-SL4-004-0070				
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SD-SL4-004-0080		V		
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or Write ID Number Here	Time:	- 1		
	2036			
Laboratory Sample Receipt RI Project Manager—Kelly Bottem		Name:	ished By	Name:
MEC Project Manager—Cliff Whitmus (cliff.whitmus@amec.com 25-921-4023)	n ph	/C/-	mur	4
MEC Laboratory Coordinator—Crystal Neirby crystal.neirby@amec.com ph. 206-838-8469)		Date: / 2/	22/14	Date: 12/22/14
Sediment samples are unhomogenized. Samples must be thoro	suahly	Time:		Time:

1645

Sediment samples are unhomogenized. Samples must be thoroughly homogenized before analysis.

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3500 188th St. SW, Suite 601 Lynnwood,WA 98037 (425) 921-4000

Sediment samples are unhomogenized. Samples must be thoroughly homogenized before analysis.

CHAIN OF CUSTODY

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SD-SL4-006-0030		1 - 7		
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Laboratory Sample Receipt		Relinquish	ned By	Received By
ARI Project Manager—Kelly Bottem AMEC Project Manager—Cliff Whitmus (cliff whitmus@amec.com	n ph	Name:	Nar Nar	
425-921-4023) AMEC Laboratory Coordinator—Crystal Neirby	1000	Date:	_/ _ Dai	e:

Time:

AMEC 3500 188th St. SW, Suite 601 Lynnwood,WA 98037 (425) 921-4000

CHAIN OF CUSTODY

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AMEC: Slip 4 Sampling	Date:				Number of containers
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Laboratory Sample Receipt		Relin	quished By		Received By
RI Project Manager—Kelly Bottem		Name:	-4	Nar	me:
AMEC Project Manager—Cliff Whitmus (cliff whitmus@amec.com ph 125-921-4023)		Date:	14216	> ✓ ≤ Dat	
MEC Laboratory Coordinator—Crystal Neirby crystal neirby@amec.com ph. 206-838-8469)		1	15/15	Cal	ilishs
Sediment samples are unhomogenized. Samples must be thoroughly homogenized before analysis.	у	Time:	738	Tim	ne: 1730

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3500 188th St. SW, Suite 601 Lynnwood,WA 98037 (425) 921-4000

CHAIN OF CUSTODY

		Analysis Containers	
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AMEC: Slip 4 Sampling	Date:		Number of containers
SD-SL4-008-0000			
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SD-SL4-008-0010			
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Pate: 1//15 Time: AMEC: Slip 4 Sampling	Date:		Number of containers
SD-SL4-008-0060	1		Number of containers
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Date: 1//15 Time:			
Laboratory Sample Receipt RI Project Manager—Kelly Bottem		Relinquished By Name;	Received By Name:

425-921-4023)
AMEC Laboratory Coordinator—Crystal Neirby (crystal neirby@amec.com ph. 206-838-8469) Sediment samples are unhormogenized. Samples must be thoroughly

homogenized before analysis.

Relinquished By	Received By	
Name:	Name:	
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3500 188th St. SW, Suite 601 Lynnwood,WA 98037 (425) 921-4000

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CHAIN OF CUSTODY

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AMEC: Slip 4 Sampling	Date:	T P F A	∢	Number of containers
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Lauviatory cample (1000)p.		Relinquist Name:		Received By
ARI Project Manager—Kelly Bottem AMEC Project Manager—Cliff Whitmus (cliff.whitmus@amec.com.ph 425-921-4023)			Mercan	ame:
AMEC Laboratory Coordinator—Crystal Neirby crystal.neirby@amec.com ph. 206-838-8469)		Date:	-/ D	ate:
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3500 188th St. SW, Suite 601 Lynnwood,WA 98037 (425) 921-4000

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SD-SL4-012-0030			1
COC Form	Time:		
AMEC: Slip 4 Sampling	Date		Number of containers
SD-SL4-012-O040			1
COC Form	Time:		
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Laboratory Sample Receipt		Relinquished By	. Received By
ARI Project Manager—Kelly Bottem		Name: 1	Name:

AMEC Project Manager—Cliff Whitmus (cliff whitmus@amec.com ph 425-921-4023)

AMEC Laboratory Coordinator—Crystal Neirby (crystal.neirby@amec.com ph. 206-838-8469)

Sediment samples are unhomogenized. Samples must be thoroughly homogenized before analysis.

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Data Validation Report

cari@saylerdata.com

DATA VALIDATION REPORT

Boeing Plant 2 Slip 4 Sediment Samples - December 2014 through January 2015

Prepared for:

AMEC Foster Wheeler 3500 188th Street SW, Ste 601 Lynnwood, WA 98037-4763

June 11, 2015

1.0 Introduction

Data Validation was performed on the following sediment samples:

Sample ID	Sample Date/Time	Lab Sample ID	Analyses
SD-PCC001-A	12/09/14 12:19	ZN96A	PCBs, Metals, TOC and TS
SD-PCC001-B	12/09/14 12:19	ZN96B	PCBs, Metals, TOC and TS
SD-PCC001-C	12/09/14 12:19	ZN96C	PCBs, Metals, TOC and TS
SD-PCC002-A	12/09/14 11:58	ZN96D	PCBs, Metals, TOC and TS
SD-PCC002-B	12/09/14 11:58	ZN96E	PCBs, Metals, TOC and TS
SD-PCC002-C	12/09/14 11:58	ZN96F	PCBs, Metals, TOC and TS
SD-PCC003-A	12/08/14 11:55	ZN89A	PCBs, Metals, TOC and TS
SD-PCC003-B	12/08/14 11:55	ZN89B	PCBs, Metals, TOC and TS
SD-PCC003-C	12/08/14 11:55	ZN89C	PCBs, Metals, TOC and TS
SD-PCC003-D	12/08/14 11:55	ZP21A	PCBs, TOC and TS
SD-PCC004-A	12/08/14 10:49	ZN89D	PCBs, Metals, TOC and TS
SD-PCC004-B	12/08/14 10:49	ZN89E	PCBs, Metals, TOC and TS
SD-PCC004-C	12/08/14 10:49	ZN89F	PCBs, Metals, TOC and TS
SD-PCC005-A	12/08/14 11:25	ZN89G	PCBs, Metals, TOC and TS
SD-PCC005-B	12/08/14 11:25	ZN89H	PCBs, Metals, TOC and TS
SD-PCC005-C	12/08/14 11:25	ZN89I	PCBs, Metals, TOC and TS
SD-SL4-001-0000	12/22/14 09:50	ZQ52A	PCBs, TOC and TS
SD-SL4-001-0010	12/22/14 09:50	ZQ52B	PCBs, TOC and TS
SD-SL4-001-0020	12/22/14 09:50	ZQ52C	PCBs, TOC and TS
SD-SL4-001-0030	12/22/14 09:50	ZQ52D	PCBs, TOC and TS
SD-SL4-001-0040	12/22/14 09:50	ZQ52E	PCBs, TOC and TS
SD-SL4-001-0050	12/22/14 09:50	ZQ52F	PCBs, TOC and TS
SD-SL4-001-0060	12/22/14 09:50	ZQ52G	PCBs, TOC and TS
SD-SL4-001-0070	12/22/14 09:50	ZQ52H	PCBs, TOC and TS
SD-SL4-001-0080	12/22/14 09:50	ZQ52I	PCBs, TOC and TS
SD-SL4-002-0000	12/22/14 10:19	ZQ52J	PCBs, TOC and TS
SD-SL4-002-0010	12/22/14 10:19	ZQ52K	PCBs, TOC and TS
SD-SL4-002-0020	12/22/14 10:19	ZQ52L	PCBs, TOC and TS
SD-SL4-002-0030	12/22/14 10:19	ZQ52M	PCBs, TOC and TS

SD-SL4-002-0040	Sample ID	Sample Date/Time	Lab Sample ID	Analyses
SD-SL4-002-0060				
SD-SL4-002-0060				
SD-SL4-002-0070				·
SD-SL4-002-0080		I .		
SD-SL4-003-0000				· · · · · · · · · · · · · · · · · · ·
SD-SL4-003-0010				
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SD-SL4-003-0030				
SD-SL4-003-0040				
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SD-SL4-004-0070 12/22/14 10:49 ZQ53R PCBs, TOC and TS SD-SL4-004-0080 12/22/14 10:49 ZQ53S PCBs, TOC and TS SD-SL4-005-0000 01/15/15 10:28 ZT01A PCBs, TOC and TS SD-SL4-005-0010 01/15/15 10:28 ZT01B PCBs, TOC and TS SD-SL4-005-0020 01/15/15 10:28 ZT01D PCBs, TOC and TS SD-SL4-005-0030 01/15/15 10:28 ZT01D PCBs, TOC and TS SD-SL4-005-0040 01/15/15 10:28 ZT01E PCBs, TOC and TS SD-SL4-005-0050 01/15/15 10:28 ZT01F PCBs, TOC and TS SD-SL4-005-0050 01/15/15 10:28 ZT01F PCBs, TOC and TS SD-SL4-005-0060 01/15/15 10:28 ZT01F PCBs, TOC and TS SD-SL4-005-0060 01/15/15 10:28 ZT01G PCBs, TOC and TS SD-SL4-006-0000 01/15/15 09:52 ZT01H PCBs, TOC and TS SD-SL4-006-0010 01/15/15 09:52 ZT01H PCBs, TOC and TS SD-SL4-006-0010 01/15/15 09:52 ZT01J PCBs, TOC and TS SD-SL4-006-0030 01/15/15 09:52 ZT01K PCBs, TOC and TS SD-SL4-006-0030 01/15/15 09:52 ZT01K PCBs, TOC and TS SD-SL4-006-0040 01/15/15 09:52 ZT01L PCBs, TOC and TS SD-SL4-006-0050 01/15/15 09:52 ZT01M PCBs, TOC and TS SD-SL4-006-0060 01/15/15 09:52 ZT01M PCBs, TOC and TS SD-SL4-006-0060 01/15/15 09:52 ZT01K PCBs, TOC and TS SD-SL4-007-0000 01/15/15 09:52 ZT01K PCBs, TOC and TS SD-SL4-007-0010 01/15/15 09:27 ZT02F PCBs, TOC and TS SD-SL4-007-0010 01/15/15 09:27 ZT02F PCBs, TOC and TS SD-SL4-007-0010 01/15/15 09:27 ZT02F PCBs, TOC and TS SD-SL4-007-0040 01/15/15 09:27 ZT02F PCBs, TOC and TS SD-SL4-007-0040 01/15/15 09:27 ZT02F PCBs, TOC and TS SD-SL4-007-0060 01/15/15 09:27 ZT02B PCBs, TOC and TS SD-SL4-007-0080 01/15/15 09:27 ZT02B PCBs, TOC and TS SD-SL4-007-0080 01/15/15 10:20 ZT02K PCBs, TOC and TS		I .		
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SD-SL4-007-0070 01/15/15 09:27 ZT02B PCBs, TOC and TS SD-SL4-007-0080 01/15/15 09:27 ZT02C PCBs, TOC and TS SD-SL4-008-0000 01/15/15 11:20 ZT02K PCBs, TOC and TS SD-SL4-008-0010 01/15/15 11:20 ZT02L PCBs, TOC and TS	SD-SL4-007-0050	01/15/15 09:27	ZT02J	PCBs, TOC and TS
SD-SL4-007-0070 01/15/15 09:27 ZT02B PCBs, TOC and TS SD-SL4-007-0080 01/15/15 09:27 ZT02C PCBs, TOC and TS SD-SL4-008-0000 01/15/15 11:20 ZT02K PCBs, TOC and TS SD-SL4-008-0010 01/15/15 11:20 ZT02L PCBs, TOC and TS	SD-SL4-007-0060			
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SD-SL4-008-0010 01/15/15 11:20 ZT02L PCBs, TOC and TS				
3D-3L4-000-0020	SD-SL4-008-0020	01/15/15 11:20	ZT02M	PCBs, TOC and TS
SD-SL4-008-0030 01/15/15 11:20 ZT02N PCBs, TOC and TS				
SD-SL4-008-0040 01/15/15 11:20 ZT02O PCBs, TOC and TS				,
SD-SL4-008-0050 01/15/15 11:20 ZT02P PCBs, TOC and TS				
SD-SL4-008-0060 01/15/15 11:20 ZT02Q PCBs, TOC and TS				
SD-SL4-008-0070 01/15/15 11:20 ZT02D PCBs, TOC and TS				
SD-SL4-009-0000 01/14/15 11:46 ZS77A PCBs, TOC and TS				

Sample ID	Sample Date/Time	Lab Sample ID	Analyses
SD-SL4-009-0010	01/14/15 11:46	ZS77B	PCBs, TOC and TS
SD-SL4-009-0020	01/14/15 11:46	ZS77C	PCBs, TOC and TS
SD-SL4-009-0030	01/14/15 11:46	ZS77D	PCBs, TOC and TS
SD-SL4-009-0040	01/14/15 11:46	ZS77E	PCBs, TOC and TS
SD-SL4-009-0050	01/14/15 11:46	ZS77F	PCBs, TOC and TS
SD-SL4-009-0060	01/14/15 11:46	ZS77G	PCBs, TOC and TS
SD-SL4-009-0070	01/14/15 11:46	ZS77H	PCBs, TOC and TS
SD-SL4-009-0080	01/14/15 11:46	ZS77I	PCBs, TOC and TS
SD-SL4-010-0000	01/14/15 12:30	ZS77N	PCBs, TOC and TS
SD-SL4-010-0010	01/14/15 12:30	ZS77J	PCBs, TOC and TS
SD-SL4-010-0020	01/14/15 12:30	ZS77K	PCBs, TOC and TS
SD-SL4-010-0030	01/14/15 12:30	ZS77L	PCBs, TOC and TS
SD-SL4-010-0040	01/14/15 12:30	ZS77M	PCBs, TOC and TS
SD-SL4-010-0050	01/14/15 12:30	ZS78A	PCBs, TOC and TS
SD-SL4-010-0060	01/14/15 12:30	ZS78B	PCBs, TOC and TS
SD-SL4-011-0000	01/14/15 11:11	ZS78C	PCBs, TOC and TS
SD-SL4-011-0010	01/14/15 11:11	ZS78D	PCBs, TOC and TS
SD-SL4-011-0020	01/14/15 11:11	ZS78E	PCBs, TOC and TS
SD-SL4-011-0030	01/14/15 11:11	ZS78F	PCBs, TOC and TS
SD-SL4-011-0040	01/14/15 11:11	ZS78G	PCBs, TOC and TS
SD-SL4-011-0050	01/14/15 11:11	ZS78H	PCBs, TOC and TS
SD-SL4-011-0060	01/14/15 11:11	ZS78I	PCBs, TOC and TS
SD-SL4-011-0070	01/14/15 11:11	ZS78J	PCBs, TOC and TS
SD-SL4-011-0080	01/14/15 11:11	ZS78K	PCBs, TOC and TS
SD-SL4-011-0090	01/14/15 11:11	ZS78L	PCBs, TOC and TS
SD-SL4-012-0000	01/15/15 12:49	ZT01P	PCBs, TOC and TS
SD-SL4-012-0010	01/15/15 12:49	ZT01Q	PCBs, TOC and TS
SD-SL4-012-0020	01/15/15 12:49	ZT01R	PCBs, TOC and TS
SD-SL4-012-0030	01/15/15 12:49	ZT01S	PCBs, TOC and TS
SD-SL4-012-0040	01/15/15 12:49	ZT01T	PCBs, TOC and TS

Analyses were performed by Analytical Resources, Inc. in Tukwila, Washington.

<u>Validation</u>: A summary validation was performed for these analyses. Validation was performed by Cari Sayler. Data qualifiers are summarized in section 5.0 of this report.

Analytical methods: Table 1 and table 2 of the QAPP specify the following analytical methods:

Analysis	Method
Polychorinated Biphenyls	EPA 8082 with 3665B/3660B cleanups
Metals(except mercury)	EPA 6010
Mercury	EPA 7471A
Total Organic Carbon	EPA 9060
Total Solids	160.1

These following methods were used: The most recent version of the methods for PCB (8082A) was used. ICP metals were analyzed by method 200.8 or 6010C. Total Organic Carbon (TOC) analyses were performed by Plumb, 1981, and total solids analyses were performed by EPA method 2540G. These are considered acceptable substitutions. Additionally, PCB cleanups included silica gel in addition to the specified sulfur and acid cleanups.

<u>Sample Receipt:</u> Sample chain-of-custodies and sample log-in documentation were reviewed. All requested analyses were performed.

The cooler receipt temperatures measured at upon receipt at the laboratory ranged from 1.7 to 14.2 °C. No qualifiers are assigned due to the temperatures outside the target range of 2 to 6 because the PCB, Metals, TOC, and total solids analytes are not highly susceptible to degradation and the samples were refrigerated or frozen at the laboratory.

<u>Sample number transcription:</u> Sample IDs in the electronic data deliverable (EDD) were compared to the chain-of-custody for each sample. Sample SD-SL4-001-0000 contained an extra 'S' (SSD-SL4-001-0000). The correct identifier has been used throughout this report. All other sample IDs matched the chain of custody.

2.0 PCB Analyses

Quality control analysis frequencies: The QAPP specifies that the following quality control samples be analyzed one per analytical batch or one per twenty samples, whichever is more frequent: method blank, and laboratory control sample (LCS). A matrix spike (MS) and MS duplicate (MSD) must be analyzed one per twenty samples and a regional reference material (RRM) must be analyzed one per fifty samples. In addition, surrogate compounds must be measured in each field and quality control sample. No field duplicates were required for the Slip 4 samples.

A method blank and LCS/LCSD were analyzed with each batch. 5 MS/MSD pairs and 2 RRM samples were analyzed with these 111 field samples. However, all sediment samples were initially grouped together at the laboratory and 17 MS/MSD pairs and 6 RRM samples were analyzed with 289 samples and field duplicates meeting laboratory overall frequency requirements. No qualifiers are assigned based on the Slip 4 MS/MSD and RRM frequencies being slightly below the target levels.

<u>Holding times:</u> Refrigerated sediment samples must be extracted within 14 days of collection. Frozen sediment samples must be extracted within 1 year of collection. Extracts must be analyzed within 40 days of extraction. These holding times were met.

<u>Instrument calibration:</u> Data usability criteria for calibrations include minimum correlation coefficients (R^2) of 0.990 or maximum RSDs of $\pm 20\%$ for each initial calibration, and maximum % differences of $\pm 25\%$ for each continuing calibration. These criteria were met with the following exceptions:

Lab SDG	Standard ID	Aroclor peak	Difference (%)
ZN89	12/02/14 07:37 ZB5	Aroclor 1016-4	27.2
ZQ52	01/02/15 10:30 ZB5	Aroclor 1016-1	30.7
ZQ52	01/02/15 10:30 ZB5	Aroclor 1016-3	31.7
ZQ52	01/02/15 10:30 ZB5	Aroclor 1016-4	30.6
ZQ52	01/02/15 16:40 ZB5	Aroclor 1260-1	29.1
ZQ52	01/02/15 16:40 ZB5	Aroclor 1260-2	29.9
ZQ52	01/02/15 16:40 ZB5	Aroclor 1260-5	25.5
ZQ52	01/02/15 19:51 ZB5	Aroclor 1016-1	26.0
ZQ52	01/02/15 19:51 ZB5	Aroclor 1016-3	25.5
ZQ52	01/02/15 22:42 ZB5	Aroclor 1016-1	25.3
ZQ52	01/03/15 13:46 ZB5	Aroclor 1016-1	25.4

Lab SDG	Standard ID	Aroclor peak	Difference (%)
ZQ52	01/03/15 13:46 ZB5	Aroclor 1016-3	26.5
ZQ52	01/03/15 13:46 ZB5	Aroclor 1016-4	25.9
ZQ52	01/05/15 08:29 ZB5	Aroclor 1254-4	25.3
ZQ52	01/05/15 08:29 ZB5	Aroclor 1254-5	27.1
ZQ52	01/05/15 08:48 ZB5	Aroclor 1016-1	32.2
ZQ52	01/05/15 08:48 ZB5	Aroclor 1016-2	25.9
ZQ52	01/05/15 08:48 ZB5	Aroclor 1016-3	32.9
ZQ52	01/05/15 08:48 ZB5	Aroclor 1016-4	31.7
ZQ52	01/05/15 14:13 ZB5	Aroclor 1016-1	26.0

Aroclor 1016 was not detected in the associated samples, and no qualifiers are required. The average percent difference for Aroclor 1254 (22.2) is within limits and no qualifiers are assigned. The Aroclor 1260 results associated with the 01/02/15 16:40 ZB5 standard are qualified as estimated.

<u>Laboratory blank results:</u> Criteria for blanks are that analyte concentrations must be below the RL, or below 10% of the lowest associated sample concentration. These criteria were met.

<u>Surrogate recoveries:</u> QAPP control limits were 34-141%. Surrogate recoveries are not evaluated in samples with dilution factors of 10 or more. The remaining surrogate recoveries were within QAPP and laboratory control limits.

<u>LCS recoveries:</u> QAPP control limits were 37-116%. LCS recoveries were within QAPP and laboratory control limits.

RRM recoveries: RRM Aroclor 1260 results were 100 and 140 ug/kg. Both of the SRMs were within the advisory limits of 38-167%.

MS recoveries: QAPP control limits were 37-116%. Control limits do not apply when the native concentration exceeds four times the amount spiked. Remaining MS recoveries were within QAPP and laboratory control limits.

MS/MSD RPDs: QAPP control limits were 50%. RPDs were within QAPP and laboratory control limits.

<u>Multiple reported results:</u> Unless quality control results warrant the rejection of one result, multiple reported results are evaluated according to the following guidelines

- (1) If both results are non-detects, the lower reporting limit was selected.
- (2) If one result was not detected and the other detected, the detection was selected.
- (3) If both results were detections, the following additional criteria were applied:
 - (a) If one result was off-scale and one was on-scale, the on-scale result was selected.
 - (b) If associated QC results indicated high bias, the lower concentration result was selected
 - (c) If associated QC results indicated no, low, or mixed biases, the higher concentration result was selected.

This approach is conservative, and is considered most protective of the environment. The results not selected as the best result to report are qualified R1, rejected due to the availability of better results. Samples with dilutions were reduced to a single result.

<u>Laboratory flags:</u> Various results are flagged Y to indicate elevated reporting limits. These results are qualified "UY" to clarify that the aroclor was not detected. Various results were flagged P to indicate the dual column RPD exceeded 40%. These results are qualified as estimated.

Reporting limits: RLs for various aroclors were elevated above 20 ug/Kg due to chromatographic overlap with other aroclors and necessary dilution. These samples also contained detected aroclors and the impact on the total PCB value was minimal. No qualifiers are assigned on the basis of elevated reporting limits.

Overall assessment: Documentation was found to be clear and complete. Calibration data demonstrate acceptable instrument performance. Laboratory control sample results demonstrate acceptable accuracy and precision. Multiple analysis results were reduced to the most appropriate to use. Results were estimated due to dual column variability.

Except for data replaced by another result, PCB data are acceptable for use as qualified.

3.0 Metals Analyses

<u>Quality control analysis frequencies:</u> The QAPP specifies that the following quality control samples be analyzed one per analytical batch or one per twenty samples, whichever is more frequent: method blank, and laboratory control sample (LCS). A matrix spike (MS) and laboratory duplicate must be analyzed one per twenty samples. No field duplicates were required for the Slip 4 samples.

These frequencies were met.

<u>Holding times:</u> Total or dissolved mercury samples must be analyzed within 28 days of collection. Other metals samples must be analyzed with 180 days. These criteria were met.

<u>Instrument calibration:</u> Functional guidelines criteria for calibration verifications is a maximum % difference of ±10% for ICP metals and ±15% for mercury. QAPP criterion for calibration verifications is ±10% for ICP metals and ±20% for mercury. Criteria for calibration blanks are that analyte concentrations must be between the negative RL and the positive RL. Functional guidelines criterion for detection limit standard recovery is 70-130%, and the QAPP specifies this standard must be within one RL of the true value. These criteria were met.

<u>Laboratory blank results:</u> The criterion for method blanks is that analyte concentrations must be below the PQL, or below 10% of the lowest associated sample concentration. This criterion was met.

<u>LCS recoveries:</u> QAPP control limits were 80-120%. LCS recoveries were within QAPP and laboratory control limits.

SRM recoveries: SRM concentrations were within the advisory range.

MS recoveries: QAPP control limits were 75-125% for ICP metals and 80-120% for mercury. Functional guidelines criteria for both ICP metals and mercury are 75-125%. MS recoveries are not evaluated when the native concentration exceeds four times the spike amount. The remaining MS recoveries were within QAPP and laboratory control limits with the following exception:

QC ID	Analyte	% Recovery	Lab Control Limit
SD-PCC003-A MS	Zinc	379	75 - 125

The zinc result is qualified as estimated in the native sample.

<u>Laboratory duplicate RPDs:</u> QAPP control limits were <20%. For duplicates with concentrations above five times the reporting limit, RPDs were within QAPP and laboratory control limits. For sample/duplicate pairs with concentrations below five times the reporting limit, absolute differences were within the reporting limit.

<u>Reporting limits</u>: Some RLs were elevated above QAPP levels due to dry weight calculation or sample dilution:

	Highest Reported RL	QAPP specified RL	SMS SQS
Analyte	(mg/kg)	(mg/kg)	(mg/kg)
Cadmium	0.3	0.2	5.1
Lead	3	2	450
Silver	0.4	0.3	6.1
Mercury	0.030	0.025	0.41

Each elevated RL was below the screening level and the impact on data use is minimal. No qualifiers are assigned on the basis of elevated reporting limits.

<u>Overall assessment:</u> Documentation was found to be clear and complete. Calibration data demonstrate acceptable instrument performance. Method blank, LCS, and SRM results demonstrate acceptable laboratory precision and accuracy. One zinc result was estimated based on the MS recovery.

Metals data are acceptable for use as qualified.

4.0 General Chemistry Analyses

<u>Quality control analysis frequencies:</u> For total organic carbon, a method blank, SRM, and LCS were analyzed in each batch. Five of the six batches also included a MS and a laboratory triplicate. For total solids, each batch included a method blank and laboratory triplicate. No field duplicates were required for the Slip 4 samples.

Quality control samples were sufficient to evaluate precision and accuracy as appropriate for the method.

<u>Holding times:</u> Holding times are as follows:

Analysis	Holding time if refrigerated	Holding time if frozen
TOC	28 days	6 months
Total Solids	14 days	6 months

Samples were analyzed within the holding times.

<u>Instrument calibration:</u> Instrument calibration criteria are as follows:

Analysis	Criteria
TOC	Initial calibration R ² > 0.990
	Continuing calibration recovery within 90-110%
Total Solids	Calibration mass within ± 0.1 g

These criteria were met.

<u>Laboratory blank results:</u> Criteria for method blanks are that analyte concentrations must be below the PQL, or below 10% of the lowest associated sample concentration. This criterion was met for all method blanks.

LCS recoveries: Control limits were 75-125% for TOC. These criteria were met.

<u>SRM results:</u> Control limits were 80-120% for TOC. These criteria were met with the following exception:

QC ID	Analyte	% Recovery	Lab Control Limit
SRM011815_1155	Total Organic Carbon	76.9	80 - 120

The total organic carbon result is qualified as estimated in the associated samples.

MS recoveries: Control limits were 75-125% for TOC. These criteria were met with the following exceptions:

QC ID	Analyte	% Recovery	Lab Control Limit
SD-SL4-004-0080MS	Total Organic Carbon	67.8	75 - 125
SD-SL4-002-0040MS	Total Organic Carbon	131.7	75 - 125

The total organic carbon result is qualified as estimated in the native samples.

<u>Laboratory duplicate and triplicate results</u>: Control limits were 20% for TOC and total solids. These criteria were met with the following exception:

QC ID	Analyte	RSD	Lab Control Limit
SD-SL4-004-0080LT	Total Organic Carbon	26.8	20.0

The total organic carbon result is qualified as estimated in sample SD-SL4-004-0080.

Overall assessment: Documentation was found to be clear and complete. Calibration data indicate acceptable performance. Method blank and LCS results demonstrate acceptable laboratory accuracy. Data were estimated based on laboratory triplicate and MS/MSD variability, and MS and SRM recoveries.

General chemistry results are acceptable for use as qualified.

5.0 Qualifier Summary Table

Client ID	Analyte(s)	Qualifier	Reason
PCB Analyses			
SD-PCC001-B	Aroclor 1232	UY	Clarification of Y flag
SD-PCC003-A	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available

Client ID	Analyte(s)	Qualifier	Reason
SD-PCC003-A DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available
SD-PCC003-A DL	Aroclor 1248, Aroclor 1260	UY	Clarification of Y flag
SD-PCC003-B	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available
SD-PCC003-B DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available
SD-PCC003-B DL	Aroclor 1248	UY	Clarification of Y flag
SD-PCC003-C	Aroclor 1248, Aroclor 1254	R1	Another result available
SD-PCC003-C	Aroclor 1240, Aroclor 1234	UY	Clarification of Y flag
SD-PCC003-C DL	All except Aroclor 1248, Aroclor 1254	R1	Another result available
SD-PCC003-C DL	Aroclor 1248	UY	Clarification of Y flag
SD-PCC003-D	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available
	Aroclor 1016, Aroclor 1221, Aroclor		
SD-PCC003-D DL	1232, Aroclor 1242	R1	Another result available
SD-PCC003-D DL	Aroclor 1248	UY	Clarification of Y flag
SD-PCC004-A	Aroclor 1248	UY	Clarification of Y flag
SD-PCC004-B	Aroclor 1232	UY	Clarification of Y flag
SD-PCC005-A	Aroclor 1248	UY	Clarification of Y flag
SD-SL4-001-0010	Aroclor 1260	J	High continuing calibration results
SD-SL4-001-0020	Aroclor 1260	J	High continuing calibration results
SD-SL4-001-0030	Aroclor 1260	J	High continuing calibration results
SD-SL4-001-0040	Aroclor 1260	J	High continuing calibration results
SD-SL4-001-0050	Aroclor 1260	J	High continuing calibration results
SD-SL4-001-0060	Aroclor 1260	J	High continuing calibration results
SD-SL4-001-0070	Aroclor 1260	J	High continuing calibration results
SD-SL4-002-0060	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available
SD-SL4-002-0060 DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available
SD-SL4-002-0070	Aroclor 1248	UY	Clarification of Y flag
SD-SL4-002-0080	Aroclor 1248	UY	Clarification of Y flag
SD-SL4-003-0020	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available
SD-SL4-003-0020 DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available
SD-SL4-004-0030	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available
SD-SL4-004-0030 DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available
SD-SL4-005-0000	Aroclor 1248	UY	Clarification of Y flag
SD-SL4-005-0010	Aroclor 1248	UY	Clarification of Y flag
SD-SL4-005-0020	Aroclor 1248	UY	Clarification of Y flag
SD-SL4-003-0020	Aroclor 1248	J	High dual column RPD
SD-SL4-008-0010 SD-SL4-008-0030	Aroclor 1248 Aroclor 1248	J	High dual column RPD High dual column RPD
SD-SL4-008-0050	Aroclor 1248 Aroclor 1248, Aroclor 1254	J R1	High dual column RPD
SD-SL4-009-0010			Another result available
SD-SL4-009-0010 DL	All except Aroclor 1248, Aroclor 1254	R1	Another result available
SD-SL4-009-0020	Aroclor 1248, Aroclor 1254	R1	Another result available
SD-SL4-009-0020 DL	All except Aroclor 1248, Aroclor 1254	R1	Another result available
SD-SL4-009-0030 SD-SL4-009-0030 DL	Aroclor 1248, Aroclor 1254, Aroclor 1260 Aroclor 1016, Aroclor 1221, Aroclor	R1 R1	Another result available Another result available
SD-SL4-009-0030 DL SD-SL4-009-0040	1232, Aroclor 1242 Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available Another result available
	Aroclor 1246, Aroclor 1254, Aroclor 1260 Aroclor 1016, Aroclor 1221, Aroclor		
SD-SL4-009-0040 DL	1232, Aroclor 1242	R1	Another result available
SD-SL4-009-0050	Arcolor 1248, Arcolor 1254, Arcolor 1260	R1	Another result available
SD-SL4-009-0050 DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available
SD-SL4-009-0060	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available
SD-SL4-009-0060 DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available

Client ID	Analyte(s)	Qualifier	Reason
SD-SL4-009-0070	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available
SD-SL4-009-0070 DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available
SD-SL4-010-0000	Aroclor 1248	UY	Clarification of Y flag
SD-SL4-011-0040	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available
SD-SL4-011-0040 DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available
SD-SL4-011-0050	Aroclor 1248, Aroclor 1254, Aroclor 1260	R1	Another result available
SD-SL4-011-0050 DL	Aroclor 1016, Aroclor 1221, Aroclor 1232, Aroclor 1242	R1	Another result available
SD-SL4-012-0000	Aroclor 1248	J	High dual column RPD
SD-SL4-012-0020	Aroclor 1248	UY	Clarification of Y flag
SD-SL4-001-0000	Aroclor 1260	J	High continuing calibration results
Metals Analyses			
SD-PCC003-A	Zinc	J	High MS recovery
General Chemistry Ana	lyses		
SD-SL4-002-0040	Total Organic Carbon	J	High MS recovery
SD-SL4-004-0080	Total Organic Carbon	J	High lab triplicate RPD, Low MS recovery
SD-SL4-010-0050	Total Organic Carbon	J	Low RM recovery
SD-SL4-010-0060	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0000	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0010	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0020	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0030	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0040	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0050	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0060	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0070	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0080	Total Organic Carbon	J	Low RM recovery
SD-SL4-011-0090	Total Organic Carbon	J	Low RM recovery

6.0 Abbreviations and Definitions

DV Qualifier	Definition
U	The material was analyzed for, but was not detected above the level of the associated value.
UY	The reporting limit was elevated due to chromatographic overlap with related compounds. The material was analyzed for, but was not detected above the level of the associated value.
J	The analyte was positively identified. The associated numerical value is the approximate concentration of the analyte in the sample.
N	The analysis indicates the presence of an analyte for which there is presumptive evidence to make a tentative identification.
UJ	The material was analyzed for, but was not detected. The associated value is an estimate and may be inaccurate or imprecise.
R	The sample result is rejected. The presence or absence of the analyte cannot be verified and data are not usable.
R1	This sample result has been rejected in favor of a more accurate and/or precise result. The other result should be used.

Abbreviation Definition

ARI Analytical Resources, Inc.

DV Data validation

Abbreviation Definition

LCS Laboratory control sample

LCSD Laboratory control sample duplicate

MS Matrix spike

MSD Matrix spike duplicate

NA Not Applicable RL Reporting limit

RPD Relative percent difference
RRM Regional reference material
RSD Relative standard deviations
SRM Standard reference material

7.0 References

- USEPA Contract Laboratory Program National Functional Guidelines For Superfund Organic Methods Data Review, Office of Superfund Remediation and Technology Innovation, U.S. Environmental Protection Agency, June 2008, USEPA-540-R-008-01.
- USEPA Contract Laboratory Program National Functional Guidelines For Inorganic Superfund Data Review, Office of Superfund Remediation and Technology Innovation, U.S. Environmental Protection Agency, January 2010, USEPA-540-R-10-011.
- Construction and Post-Construction Sediment Monitoring Quality Assurance Project Plan, Duwamish Sediment Other Area and Southwest Bank Corrective Measure and Habitat Project, Boeing Plant 2. Prepared by AMEC Environment & Infrastructure Inc., et al. Prepared for: The Boeing Company, June 2013